

LGAD at Collider Experiments

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First Annual EICC workshop 2026

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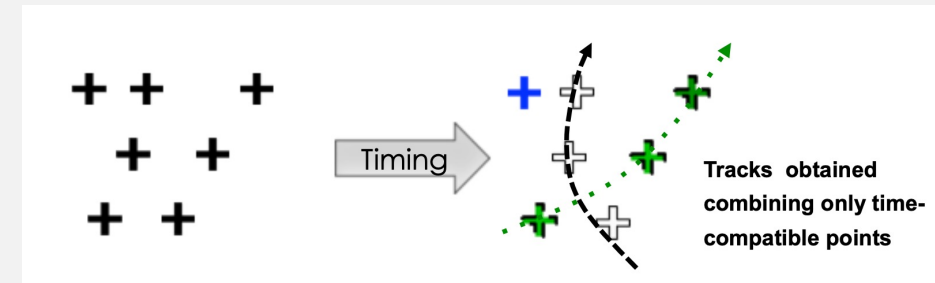
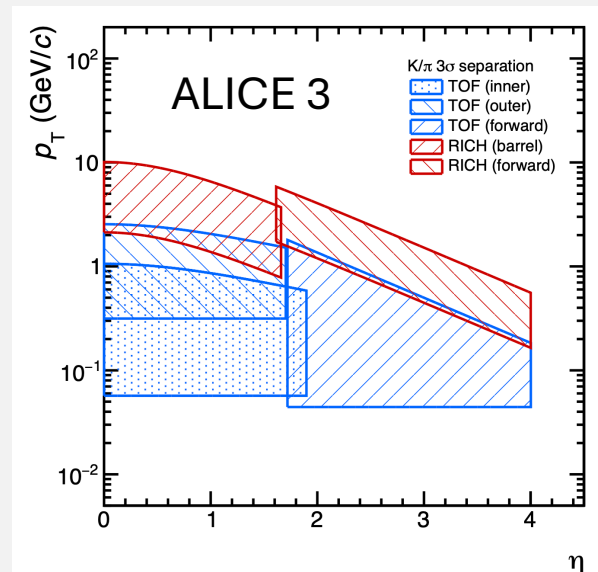
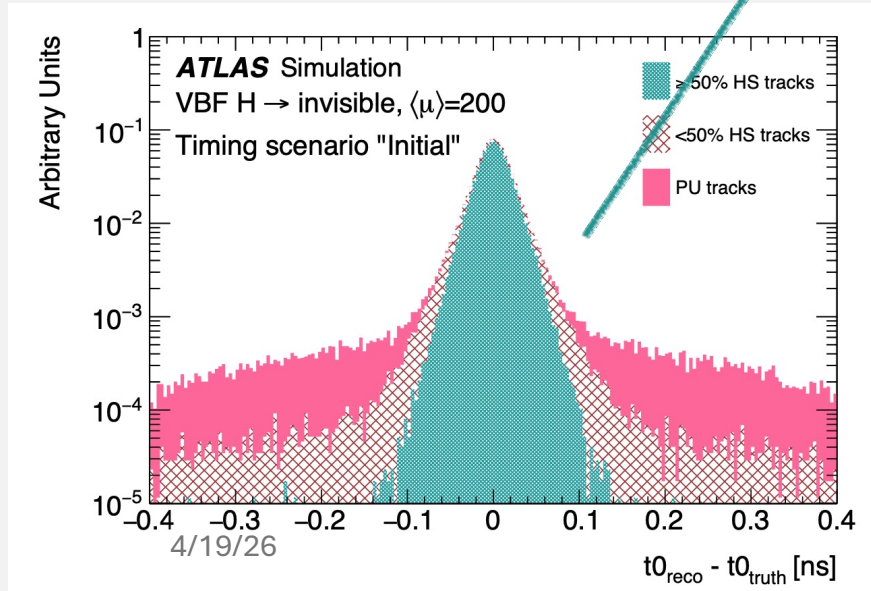
Outline

- Work principle of LGAD and early R&D
- Optimization for LHC phase 2 upgrade
- AC-LGAD for electron-ion colliders
- Trench-Isolated (TI) LGAD
- CMOS-LGAD

Applications of LGAD at collider experiments

- HL-LHC ATLAS/CMS: time information to tracks, vertices to mitigate pile-up (at peak luminosity, expect 200 pile-up per BX)
- EIC, ALICE 3 TOF for PID
- Future: 4D tracking

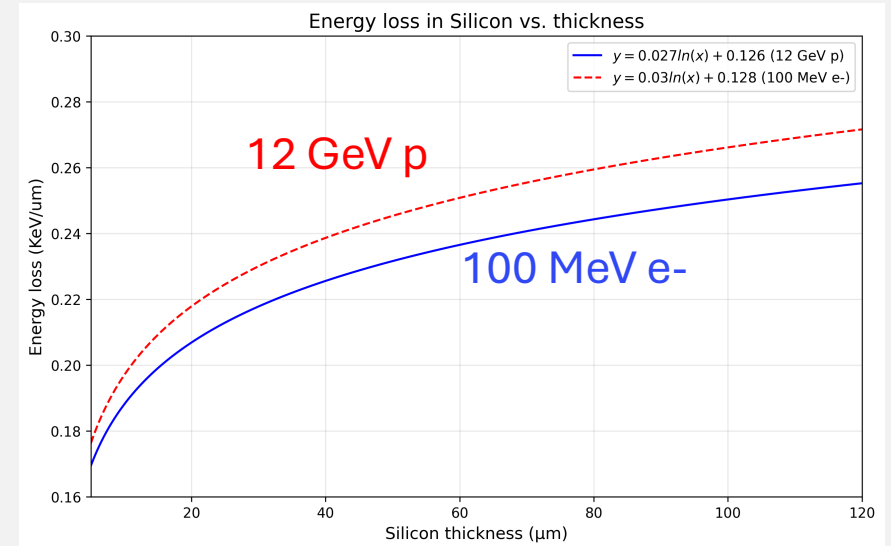
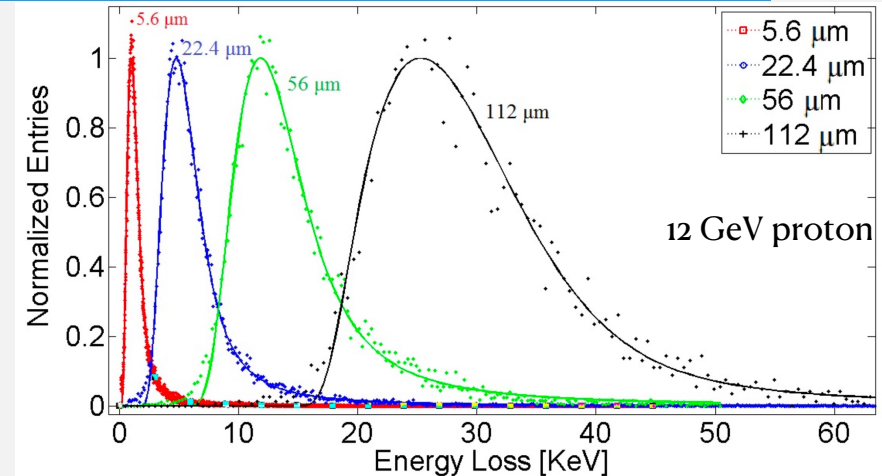
RMS = 22 ps



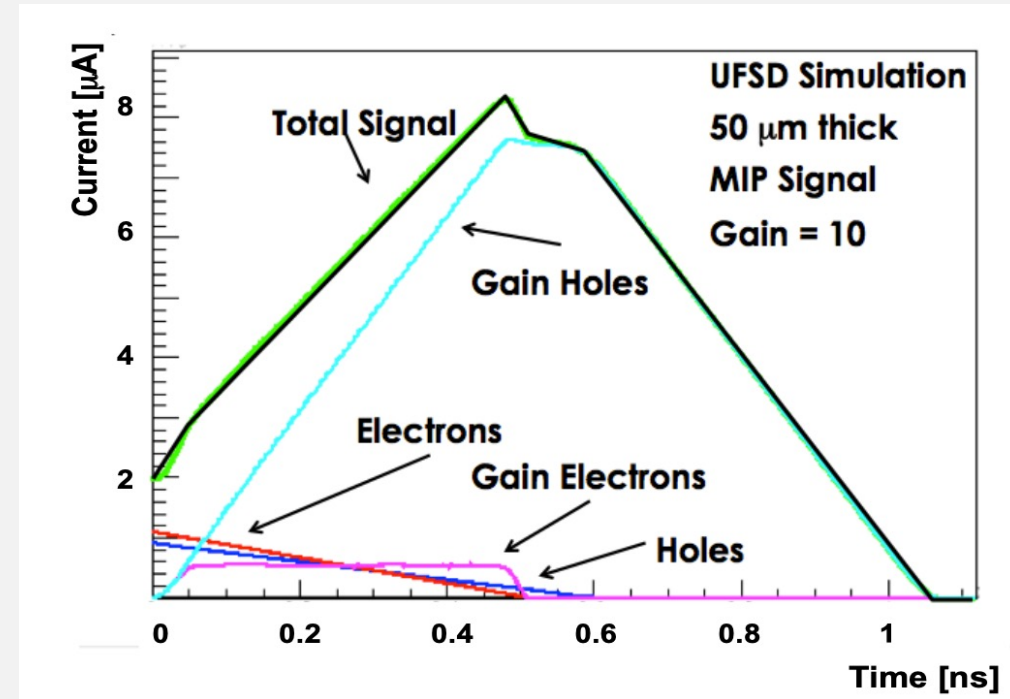
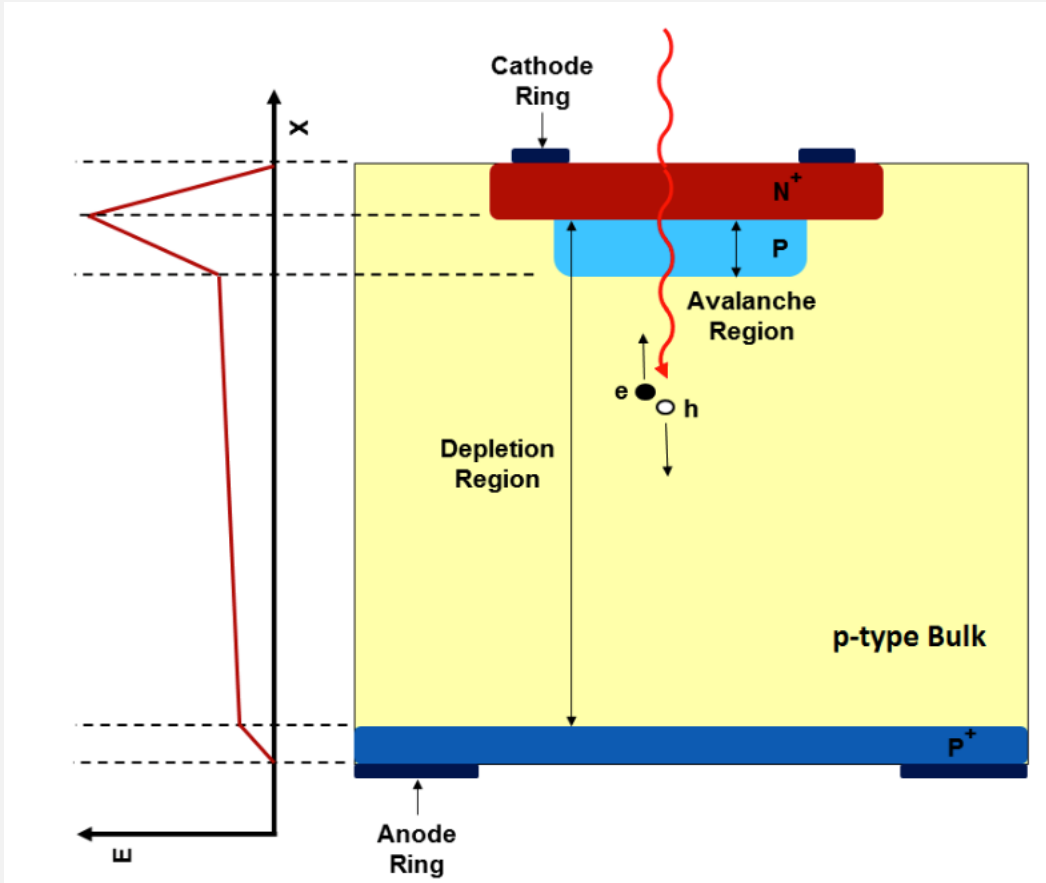
Some numbers about Silicon detectors

- MIP E loss : $0.23 \text{ keV}/\mu\text{m}$
(MPV for $50 \mu\text{m}$ thick Si)
- Average ionizing energy: 3.68 eV
- If no gain, $50 \mu\text{m} \rightarrow \sim 0.5 \text{ fC}$

LGAD	Gain: 5~20
APD	Gain: 50~1000
SiPM	Gain: $10^5 \sim 10^7$



Work principle of Low Gain Avalanche Diode



Invention of LGAD

- 21st RD50 WS **2012**: charge multiplication in irradiated silicon detectors [[talk](#)]
- 25th RD50 WS **2014**: Common project to investigate thin LGAD (talk at CB)

**Radiation hard semiconductor devices
for very high luminosity colliders**

2004-2024 (evolved to DRD3)

RD50 - Common Projects		
	Template for funding request: Funding request to RD50 (Rules are given on bottom of this page)	Reference 2014.4
August 2014	Investigation of the properties of thin LGAD; <i>Nicolo Cartiglia</i> funding request approval	2014-05
	RD50 Common Test beam at CERN; Marco Bomben (a financial support to students was granted 4 x 500 CHF)	2014-04
March 2014	Production of thin active edge pixel sensors at ADVACAM; Anna Macciolo funding request approval	2014-03
	Fabrication of 200um thick p and n- type pad detectors with enhanced multiplication effect; Giulio Pellegrini funding request approval	2014-02
	UBM for sensor wafers; Giulio Pellegrini (no cost to RD50 common fund)	2014-01



Status of CNM RD50 LGAD Project 26th RD50 Workshop. Santander. 23th June, 2015

RD50 Samples Distribution 2015.6

1. CNM Barcelona, G. Pellegrini, Giulio.Pellegrini@cnm-imb.csic.es
2. CERN, M. Moll, Michael.Moll@cern.ch
3. UC Santa Cruz, Hartmut Sadrozinski, hartmut@ucsc.edu
4. LAL Orsay, Abdenour Lunis, lounis@lal.in2p3.fr
5. IFCA Santander, Ivan Vila, ivan.vila@csic.es
6. INFN Torino, N. Cartiglia <cartiglia@to.infn.it>
7. Jozef Stefan Institute, G. Kramberger, Gregor.Kramberger@ijs.si
8. IFAE Barcelona, S. Grinstein, sgrinstein@ifae.es

First paper on LGAD (2014.6)
300 μm thick!
Established gain layer
No discussion about timing

Nuclear Instruments and Methods in Physics Research A 765 (2014) 12–16

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journal homepage: www.elsevier.com/locate/nima

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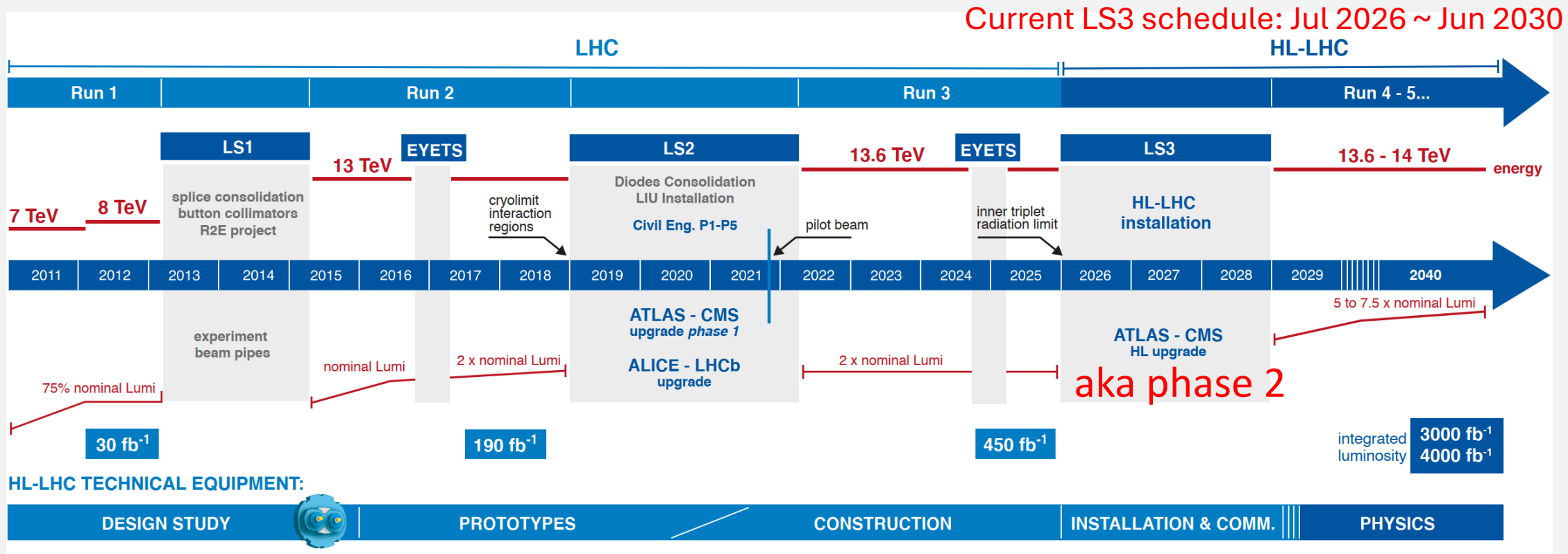
Technology developments and first measurements of Low Gain Avalanche Detectors (LGAD) for high energy physics applications

G. Pellegrini^{a,*}, P. Fernández-Martínez^a, M. Baselga^a, C. Fleta^a, D. Flores^a, V. Greco^a, S. Hidalgo^a, I. Mandić^b, G. Kramberger^b, D. Quirion^a, M. Ullan^a

^a Centro Nacional de Microelectrónica, IMB-CNM-CSIC, Barcelona, Spain
^b Jozef Stefan Institute, Jamova 39, 1000 Ljubljana, Slovenia

High-luminosity LHC schedule

Phase 2 = 87% of LHC !



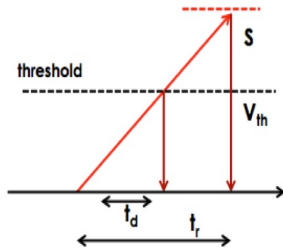
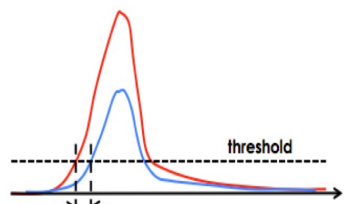
Key points for timing: low gain and thin!

- Time resolution decomposition

$$\sigma_t^2 = \sigma_{\text{Landau}}^2 + \sigma_{\text{Distortion}}^2 + \sigma_{\text{TimeWalk}}^2 + \sigma_{\text{jitter}}^2 + \sigma_{\text{TDC}}^2 + \sigma_{\text{clock}}^2$$

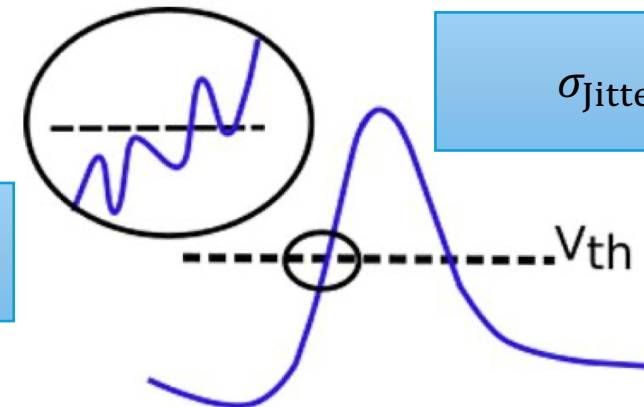
Often negligible

- Landau: fluctuation of energy deposition
 - Mitigation: thin sensors
- Distortion: non-uniformity of drift velocity and weighting field
 - Mitigation: planar and thin sensor, high E-field to saturate drift velocity
- Time-walk and jitter minimized by low noise and large slew rate



$$t_d = \frac{V_{\text{th}}}{S} t_{\text{rise}} \propto \frac{\text{Noise}}{S/t_{\text{rise}}}$$

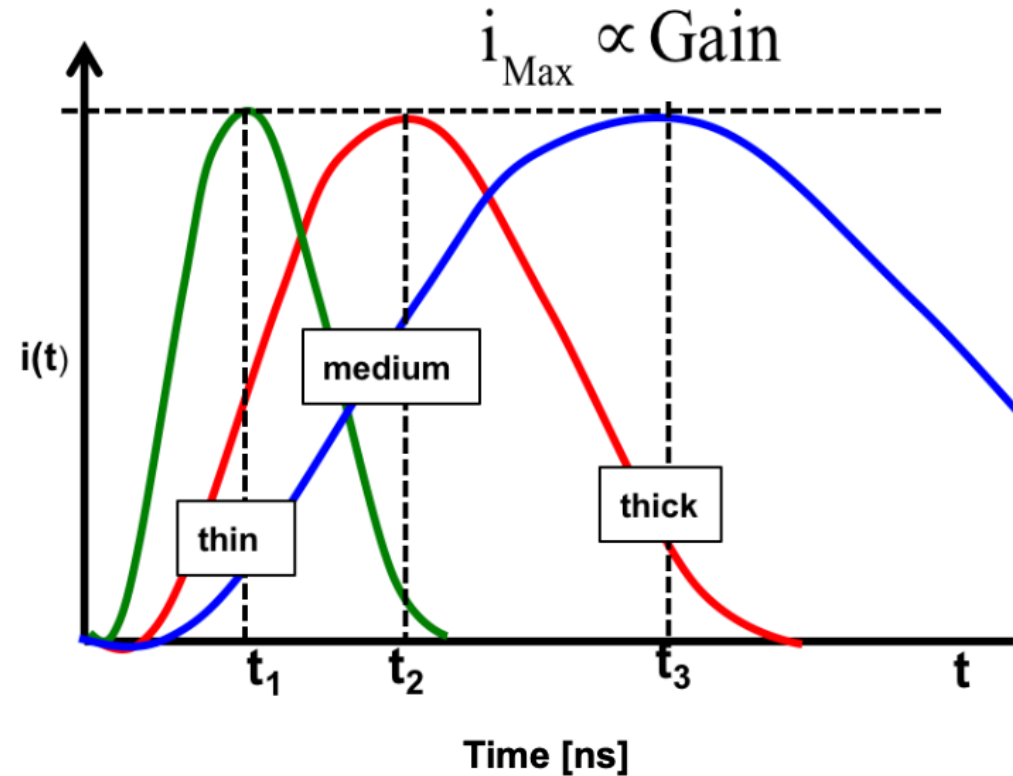
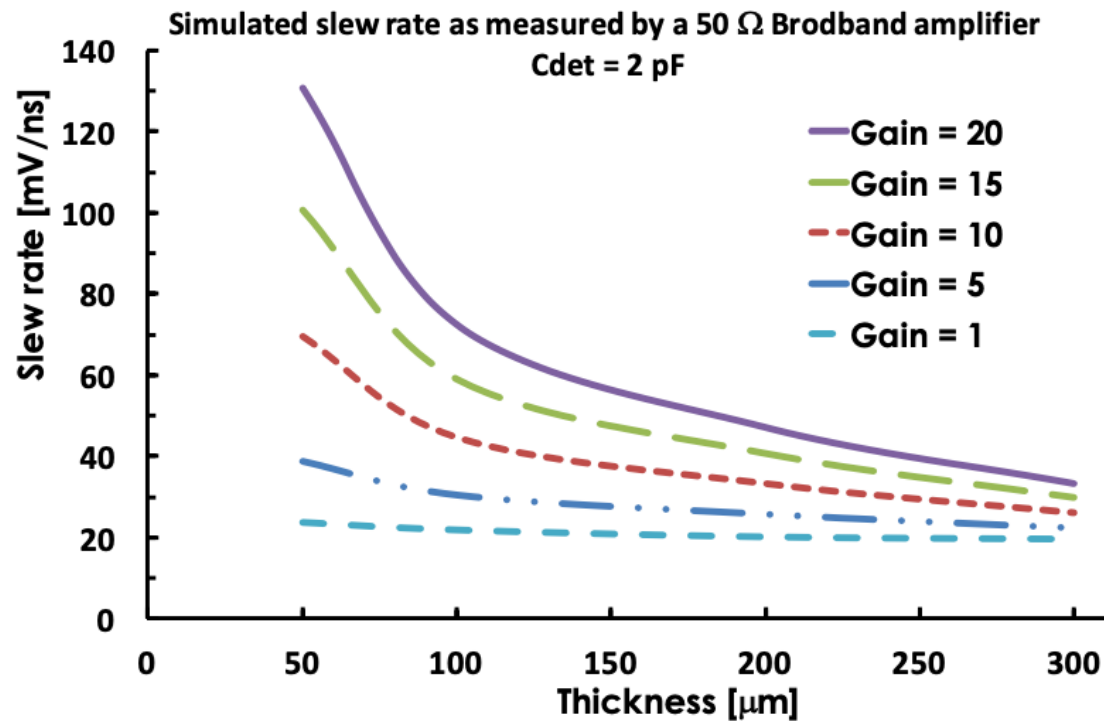
$$\sigma_{\text{TimeWalk}} \sim \text{RMS}[t_d] \sim \text{RMS}\left[\frac{\text{Noise}}{S/t_{\text{rise}}}\right]$$



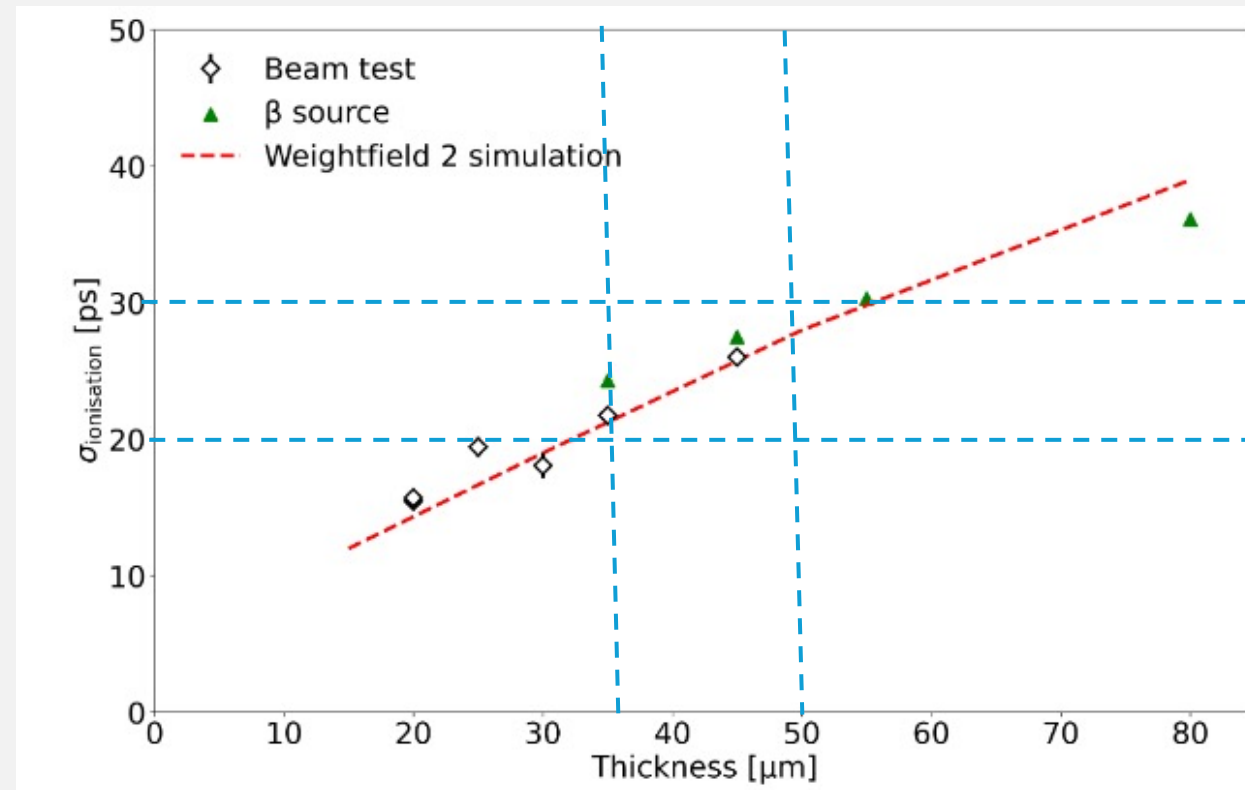
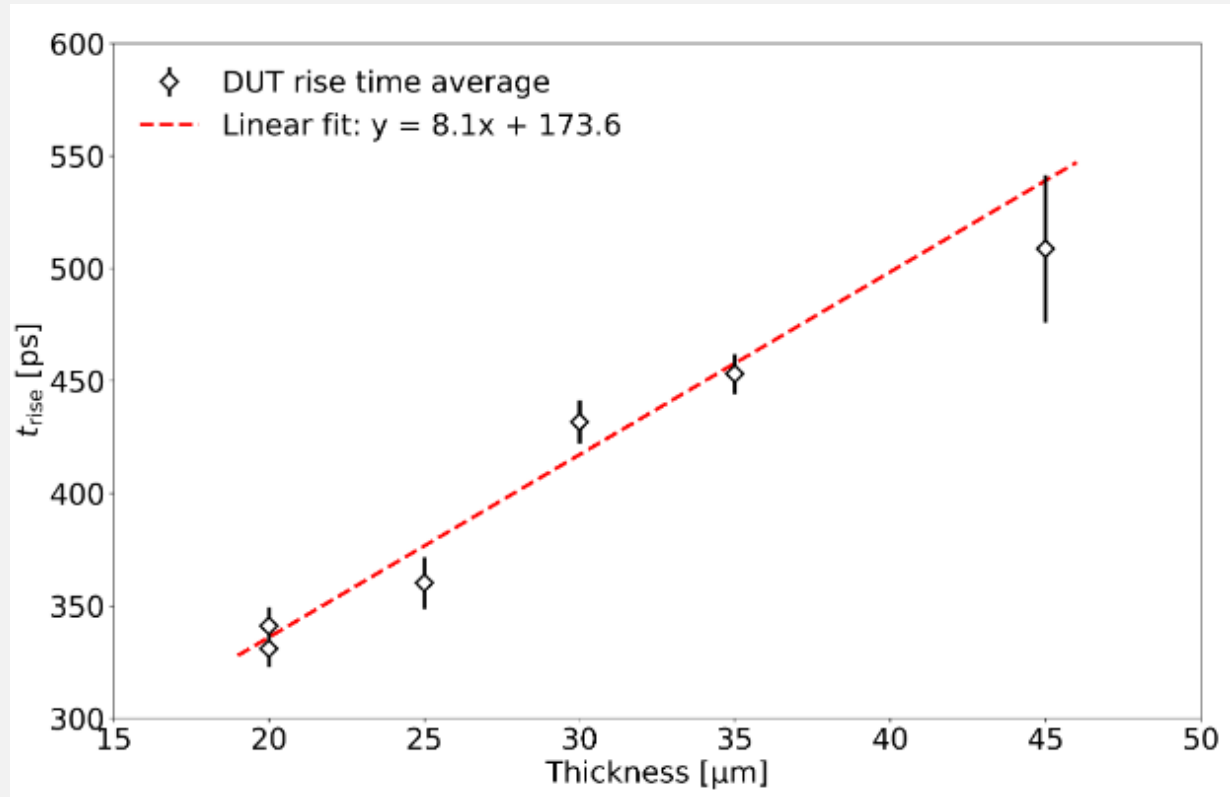
$$\sigma_{\text{jitter}} \sim \frac{\text{Noise}}{S/t_{\text{rise}}}$$

Slew rate vs. thickness

i_{\max} independent of thickness
Thinner sensor => higher slew rate



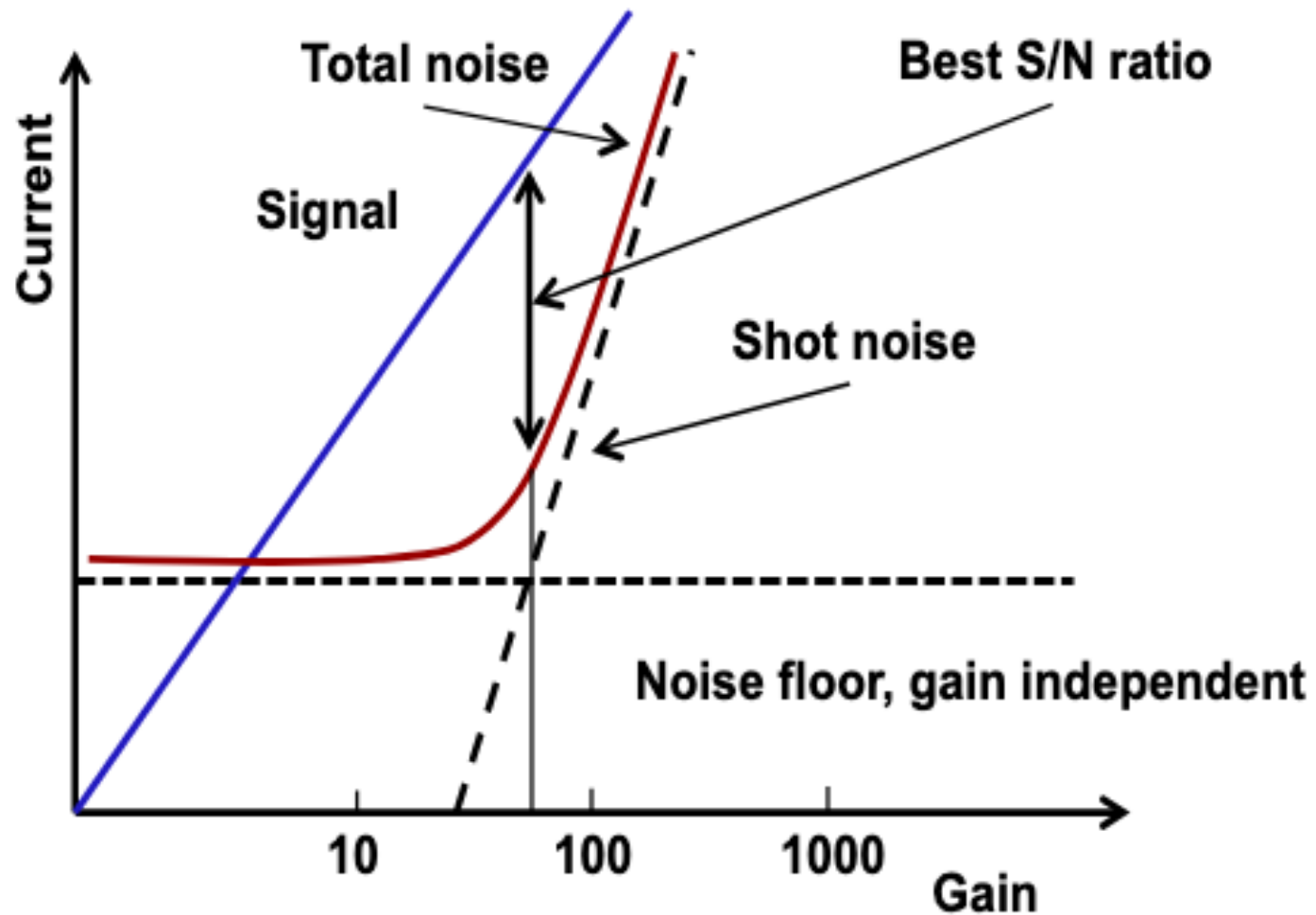
Systematic experimental verification (2025)



50 μm \rightarrow \sim 30 ps

35 μm \rightarrow \sim 22 ps

Gain optimization

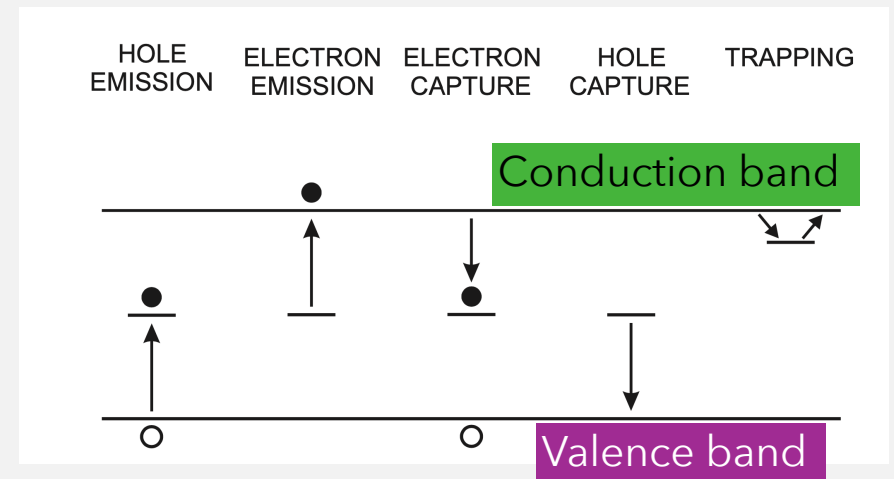
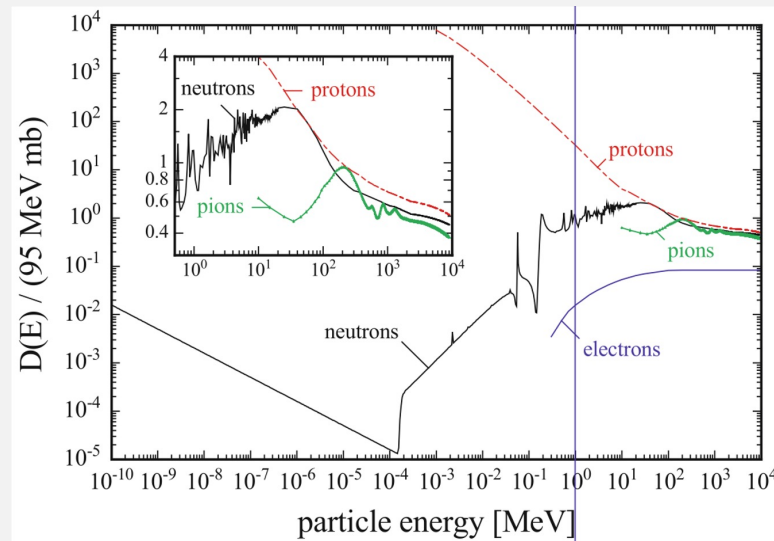


Shot noise increase with bulk leakage current
Best S/N achieved at gain of few 10s

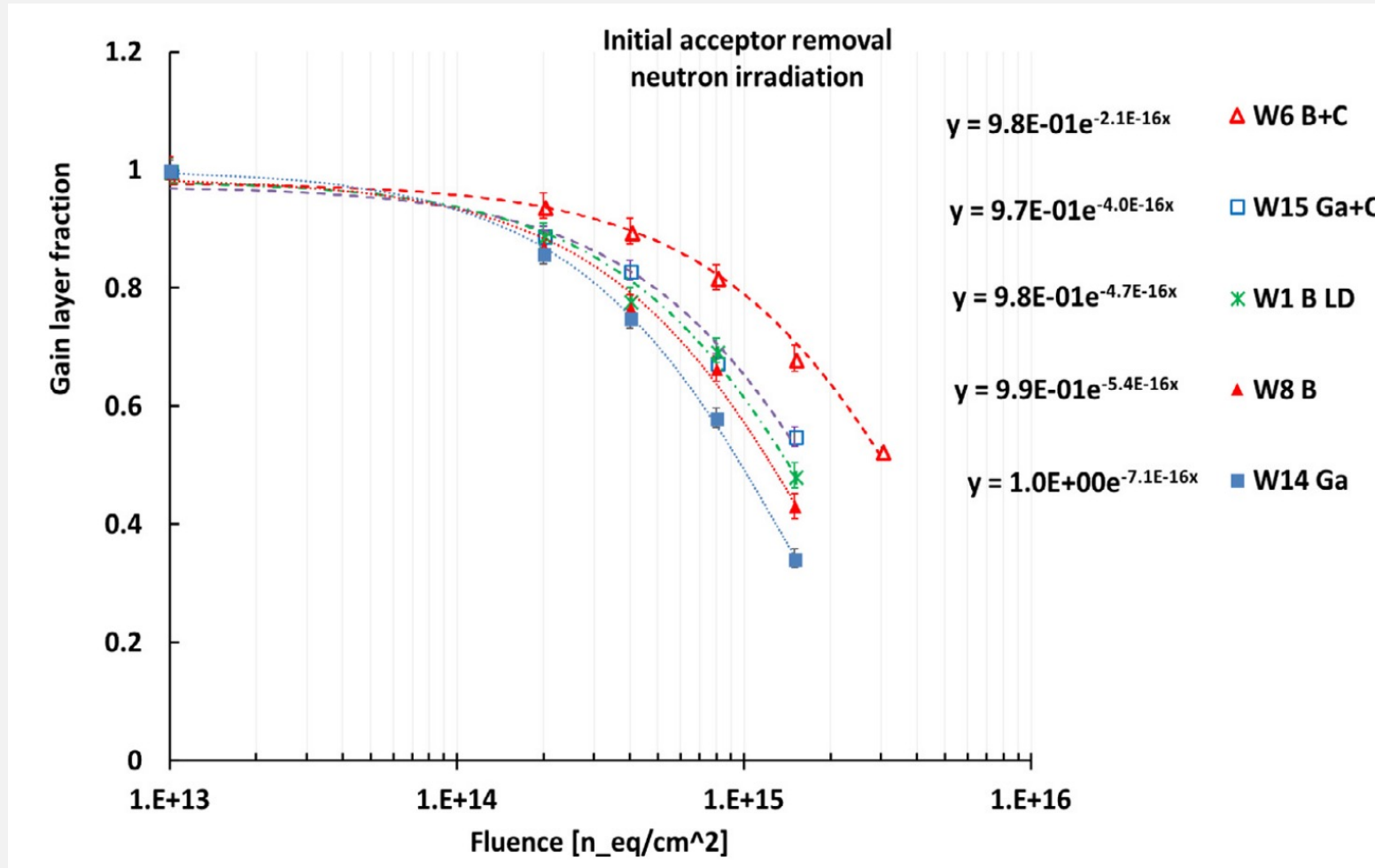
Radiation damages to LGAD

- **Ionizing damage:** energy absorbed by ionizing (1 Gy = 1 J/kg = 100 rad) in insulating layers, liberates charge carriers (less relevant for sensors)
- **Displacement damage** (displaces silicon atoms from their lattice sites)
 - Formation of mid-gap states => **increase of leakage current**
 - states close to band edges => trapping (**decrease charge collection efficiency**)
 - Inactivation of Boron doping (**Acceptor removal**)
 - Energy and particle type dependent (measured in 1 MeV neutron equivalent / cm²)

$$D(E) = \sum_v \sigma_v(E) \int_0^{E_R^{max}} f_v(E, E_R) P(E_R) dE_R$$

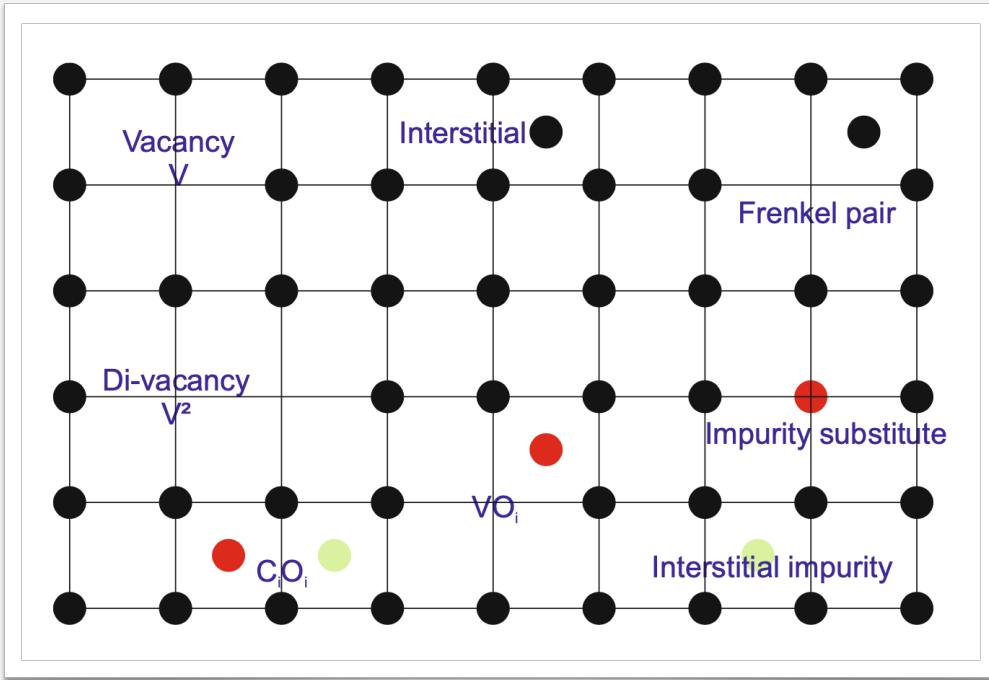


Co-implantation of gain layer

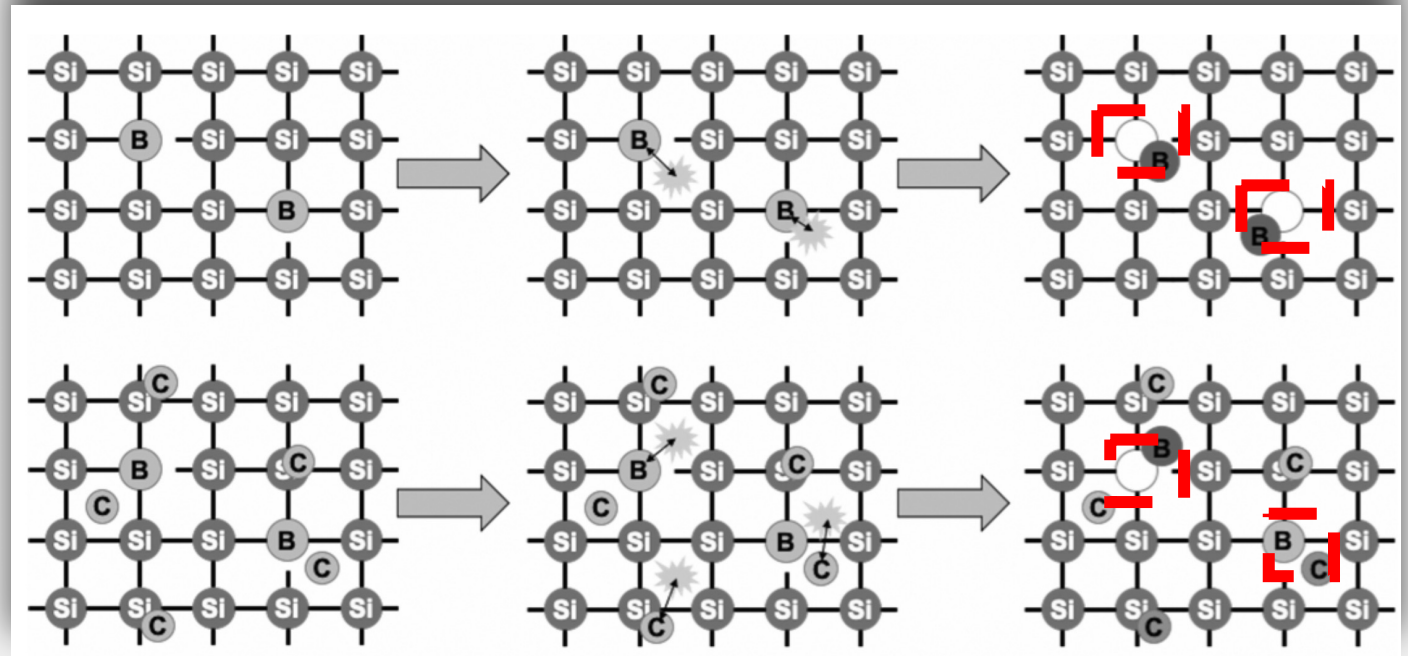


Effects of Carbon in gain layer (conjecture)

Defects in Silicon lattice



Carbon competes with Boron to form ion-defect states



Carbon implantation at gain layer:

- 1) replace Boron in ion-defect complex formation
- 2) substitutional carbon pair with interstitial Boron to form centers with energy of 80% acceptor energy level

Snapshot of sensor status in 2021

Recent productions (>2020)

Manufacturer	Name	D [μm]	GL [μm]	V _{gl} [V]	Dopant/C	SE [μm]	IP [μm]	Max. Array Size
HPK (HPK-P2) (6")	P2 (4 splits)	~50	~2.2	50.5-54.5	B/NO	300-500	30-70	Single, 2x2, 3x3, 5x5, 15x15, 15x30
FBK (6")	UFSD 3.2	~45, 55	~1-2	25-50	B/YES	500	28-49	Single, 2x2, 5x5
NDL (6")	V3, V4	~50	~1	~29	B/NO			2x2
IHEP-IME (8")	V1, V2	~50	~1	~25	B/YES			Single, 2x2, 5x5
USTC-IME (8")	V1.1, V2.0, V2.1	~50	~2	30-40	B/YES		30-90	Single, 2x2, 5x5, 15x15
CNM (6")	R12916 (AIDAv2)	~50	~1	~40	B/NO			Single, 2x2, 5x5

HPK serves as "gold standard" to which others are compared – the key results will be shown HPK

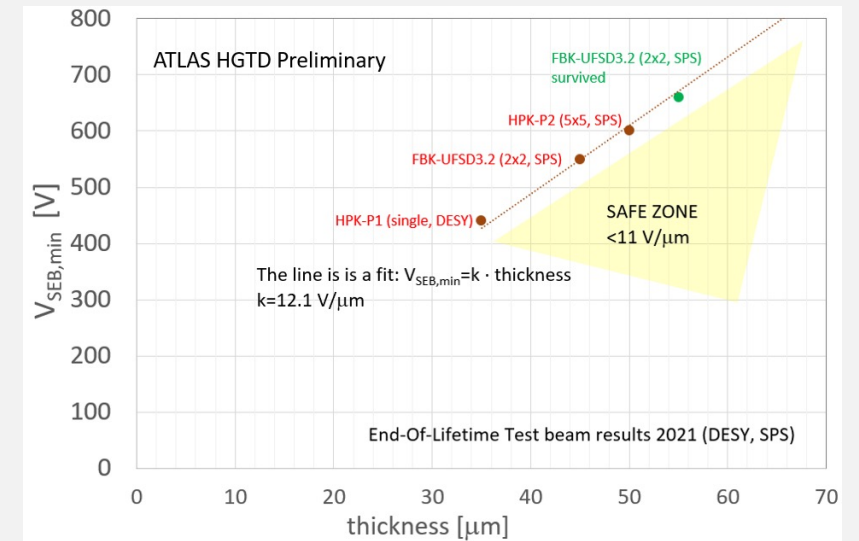
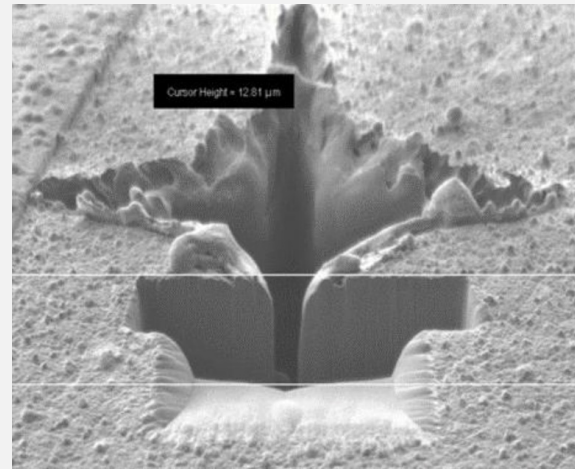
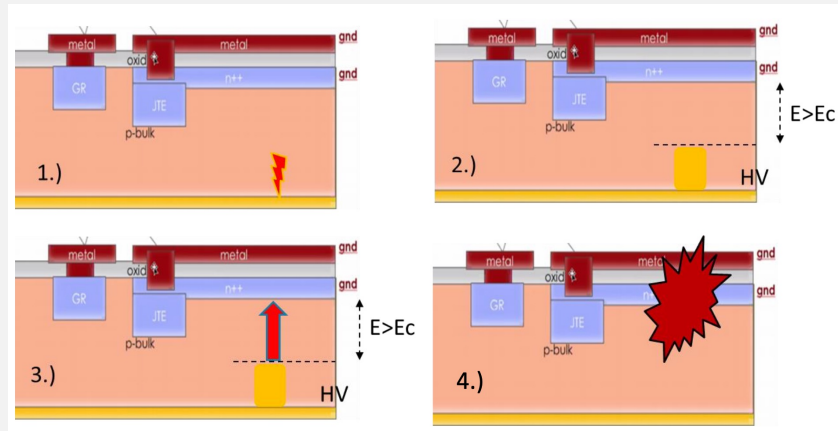
Mains specifications are in the TDRs.

The key property is collection of **4 (ATLAS) / 5 (CMS) fC** ($G \sim 8/10$) at **safe operation voltage** over the entire lifetime of the experiments ($2.5e15 \text{ cm}^{-2}$)

It was shown with discrete electronics that the required time resolution and efficiency can be achieved with $>4 \text{ fC}$ and also for expected ASICs performance $<70 \text{ ps}$ for single hit resolution.

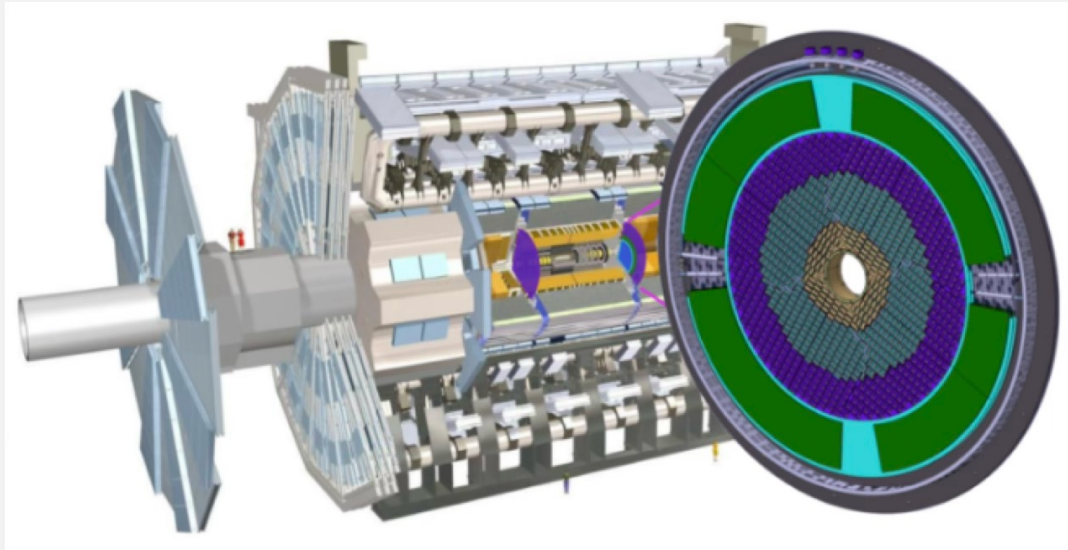
Sensor mortality

Large energy deposition → large amount of charge carriers → conductive path
→ localized high E-field (above critical E-field) → irreversible breakdown

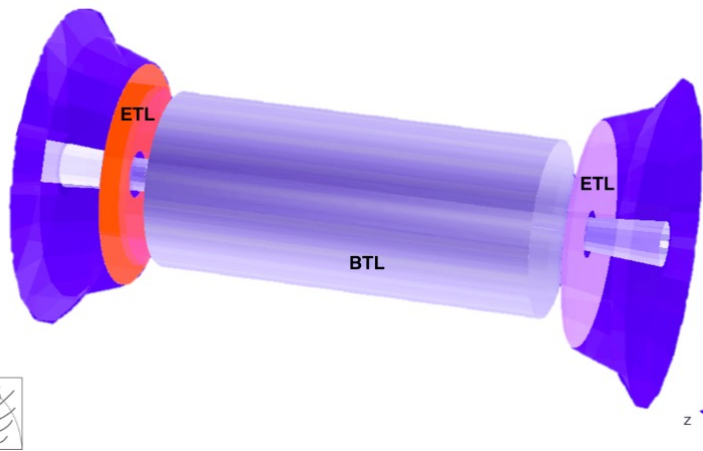


- Unrecoverable breakdown of irradiated sensors observed at proton/electron/laser beam
- “Crater” burn mark at the hit position of the beam particle
- Collaborative investigations at FNAL/DESY/ELI-Prague:
reproduceable mortality with localized large energy deposition
- Safe bias $V < 550 \text{ GeV}$ for 50 μm sensor

LGAD for ATLAS and CMS



ATLAS HGTD LGAD: 15x15 array of 1.3 mm x 1.3 mm
total active area 6.4 m²
~3.6 M channels
Suppliers: IHEP-IME, USTC-IME



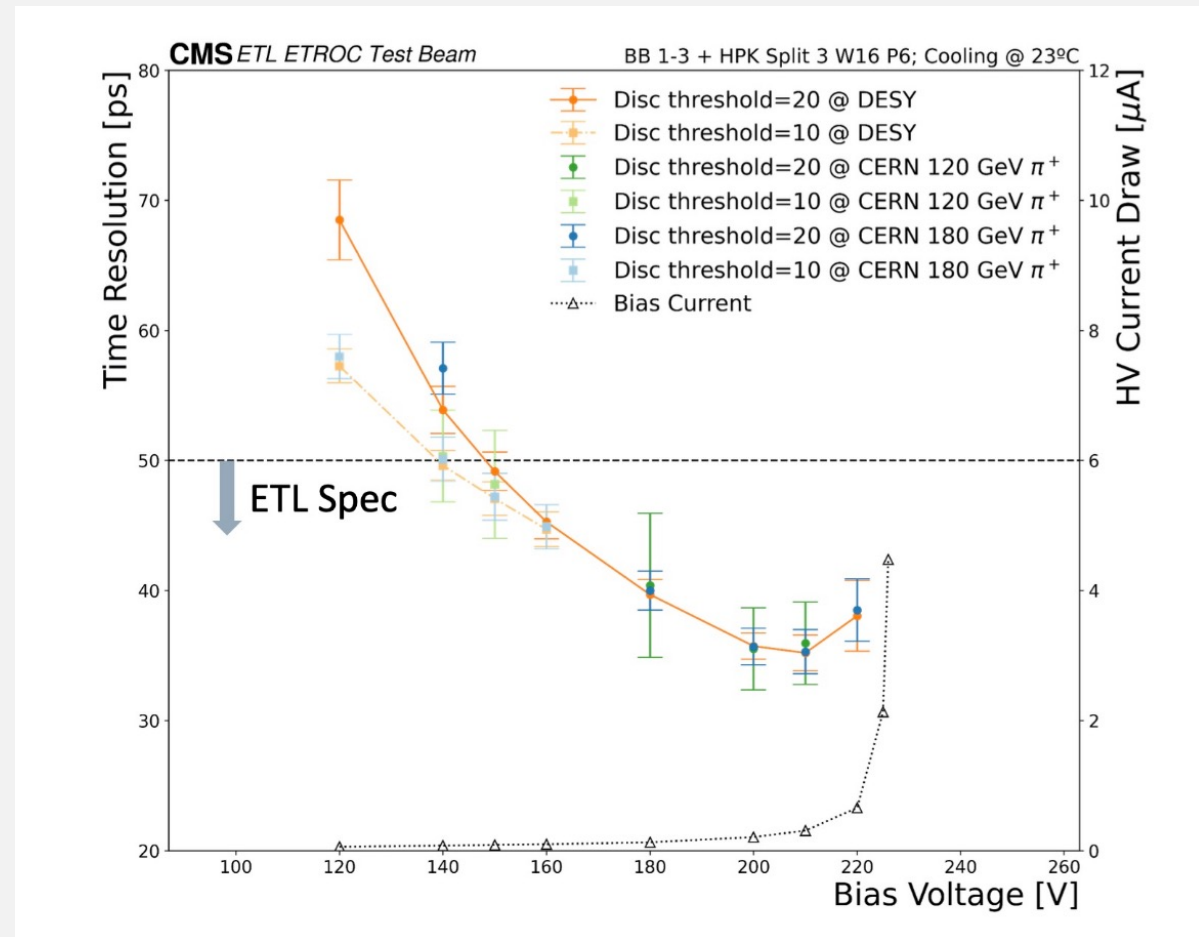
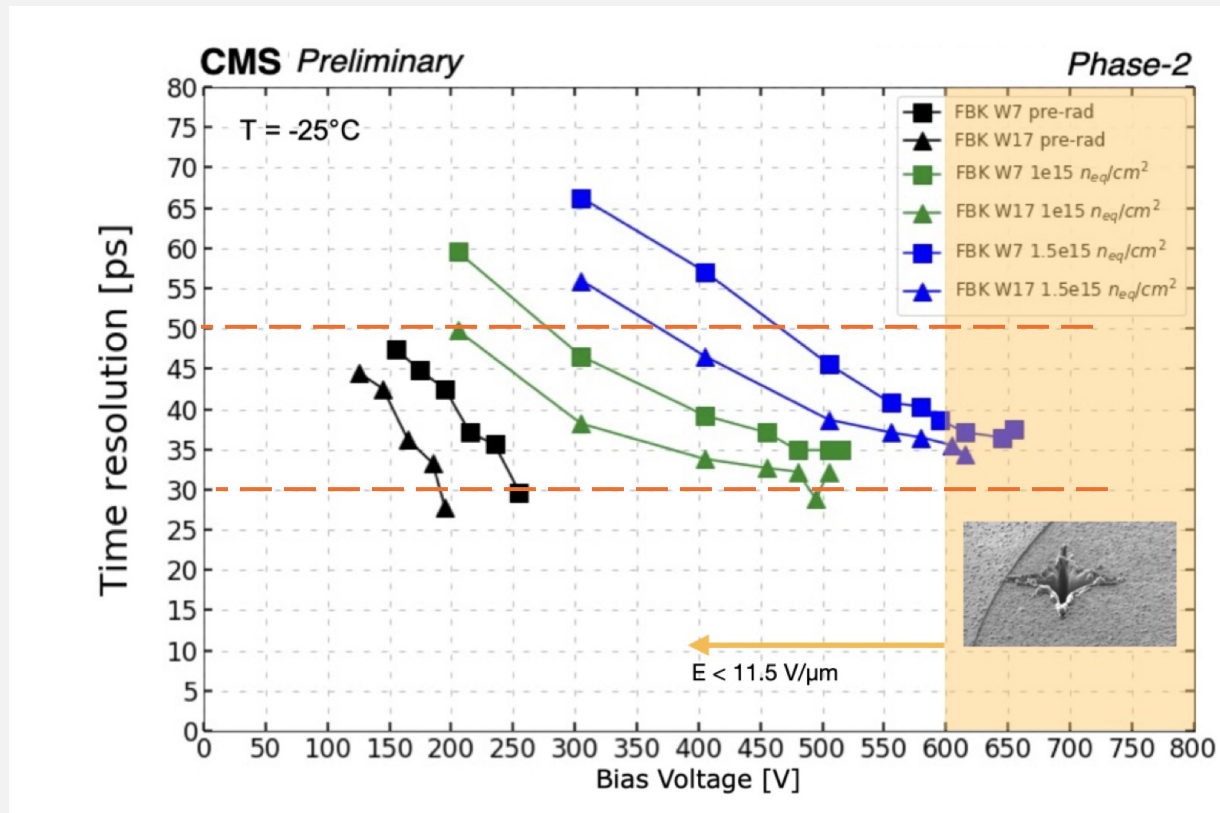
CMS ETL LGAD: 16x16 array of 1.3 mm x 1.3 mm
total active area 14.4 m²
~8.5 M channels
Suppliers: FBK (LFoundry), HPK



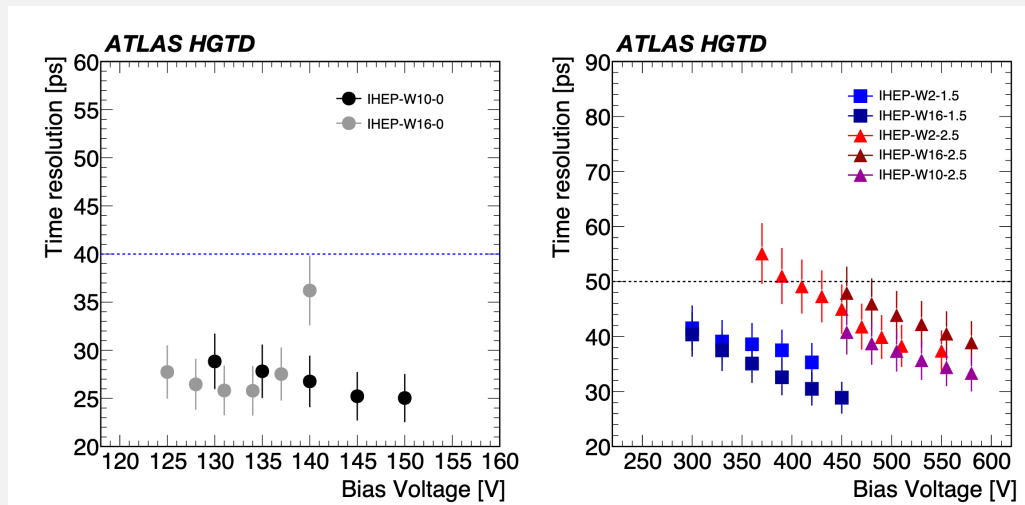
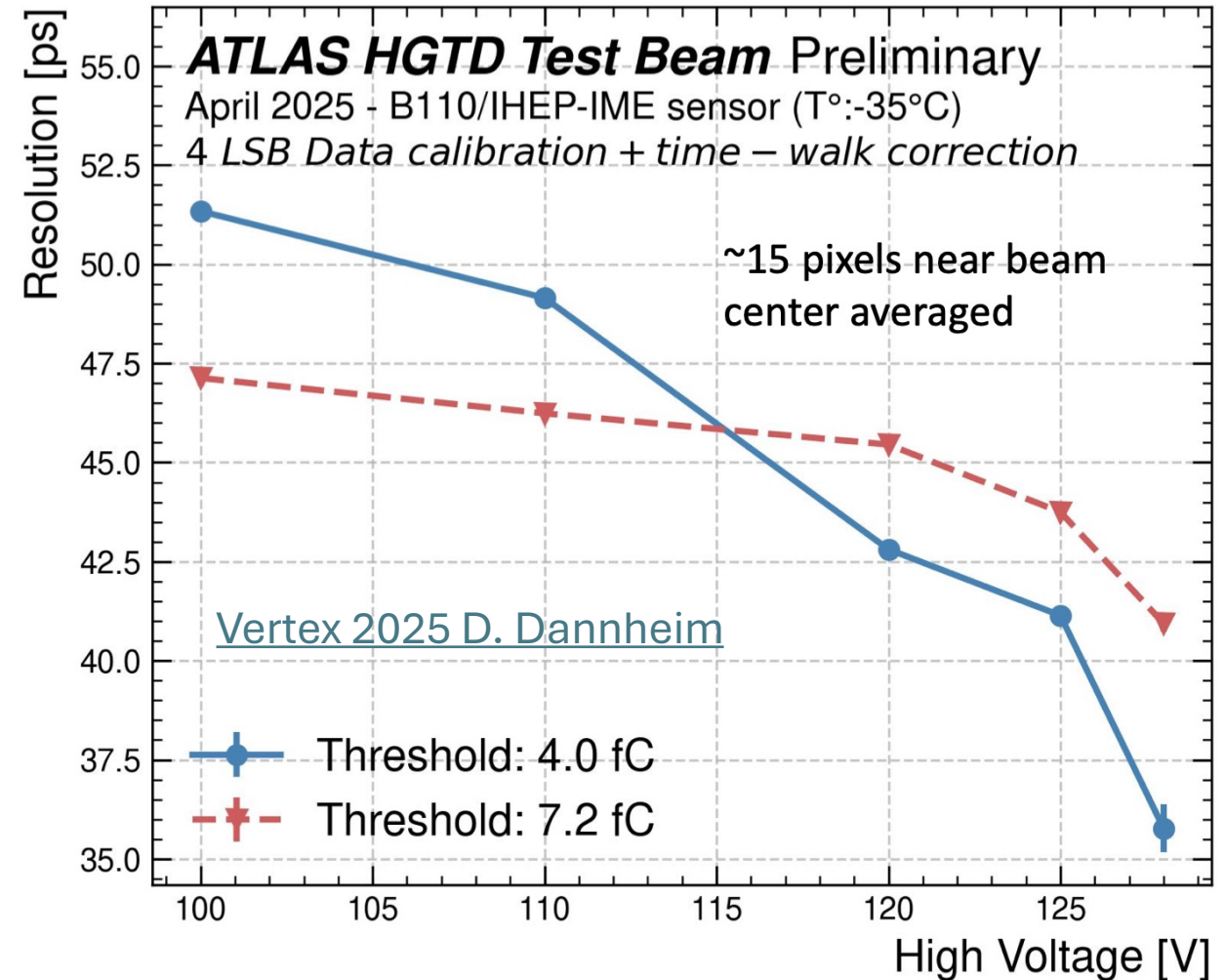
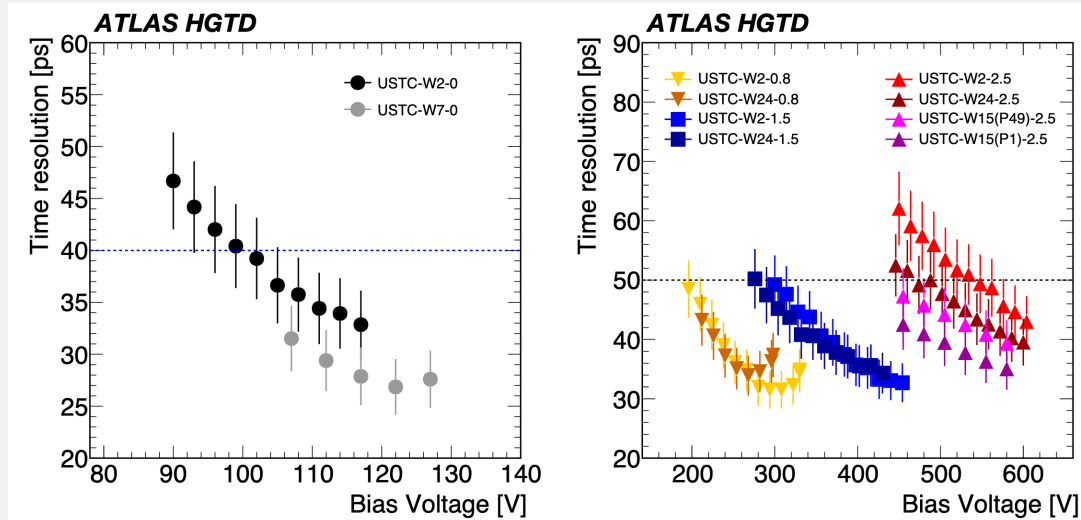
Some test results of production LGAD (CMS)

EPS HEP 2025

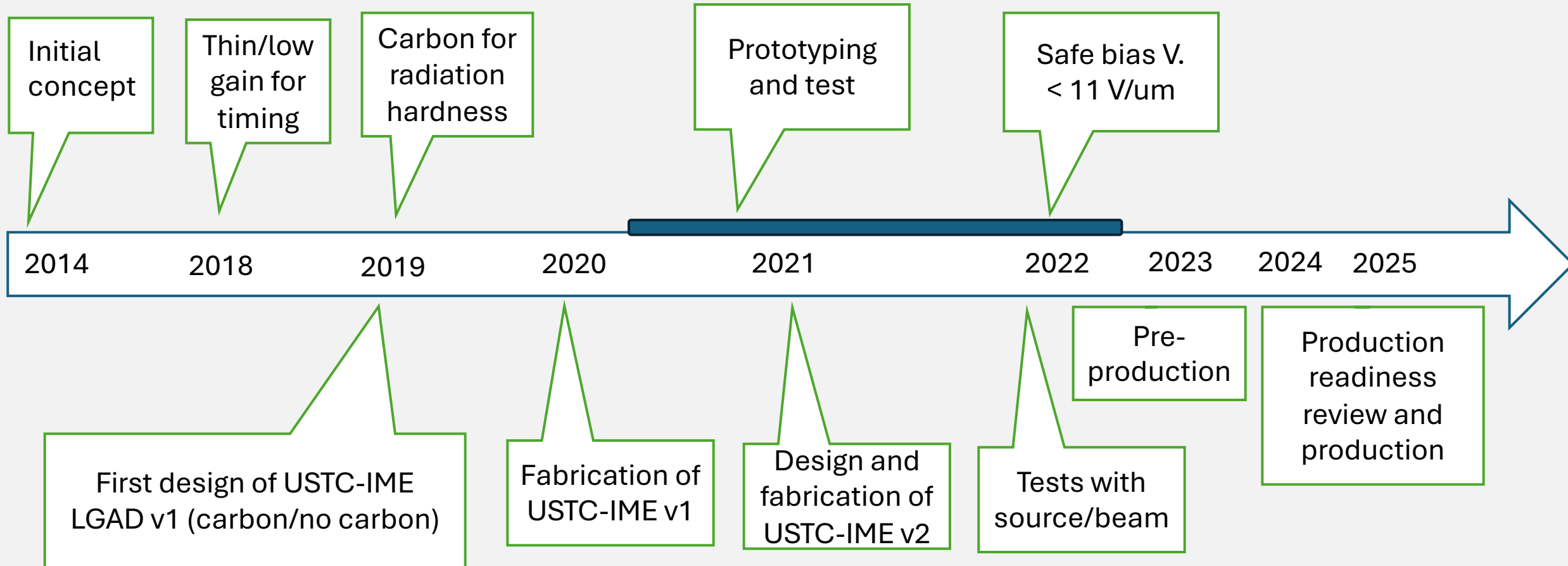
LP 2025 conference report



Some test results of production LGAD (ATLAS)



Recap of the LGAD RD for ATLAS/CMS

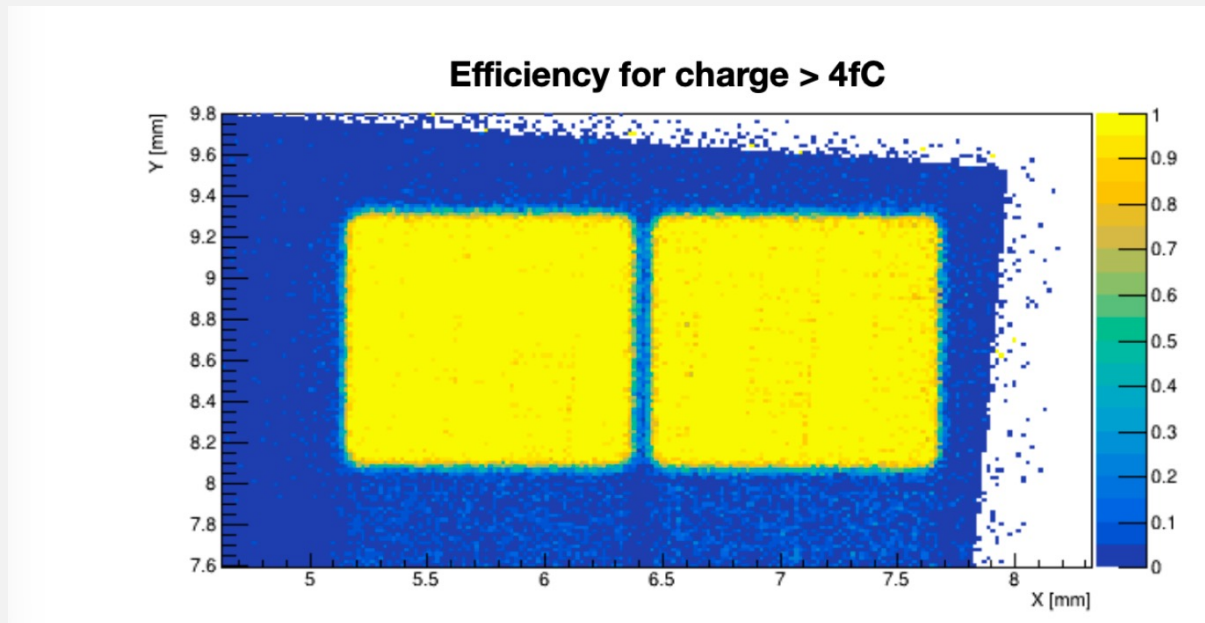
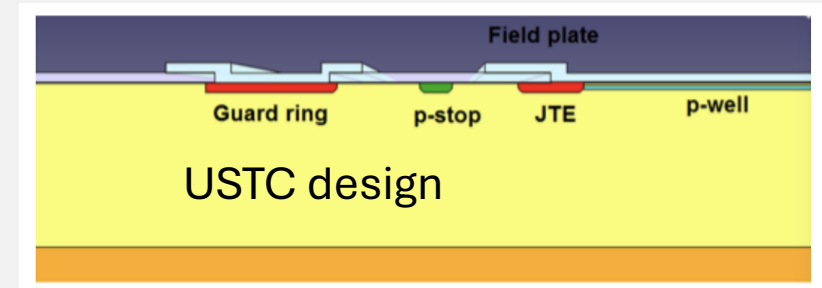


CMS ETL TDR: CERN-LHCC-2019-003

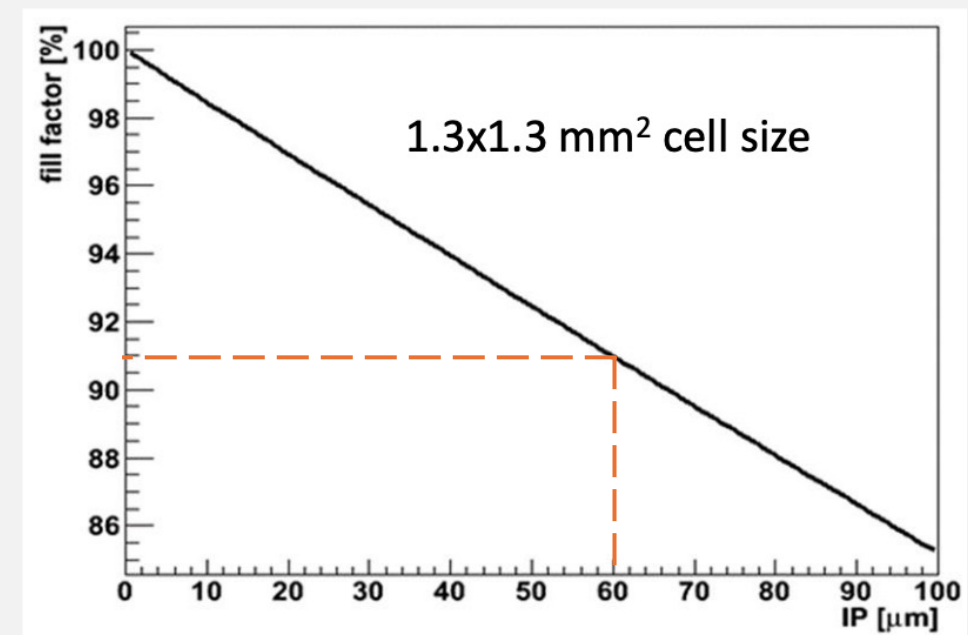
ATLAS HGTD TDR: CERN-LHCC-2020-007

Fill-factor of LGAD

- Structures at peripheral region
 - Isolation, protection and field adj. at edge
- Fill-factor = [area w. gain]/[total area]
- Limiting the pitch size of LGAD



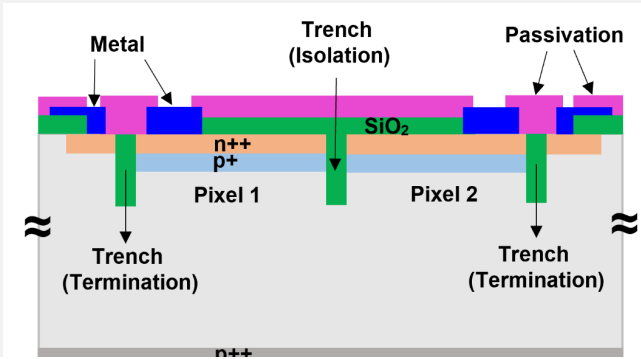
USTC-IME v2 W17-2x2 IP3:
inter-pad width = 62 um



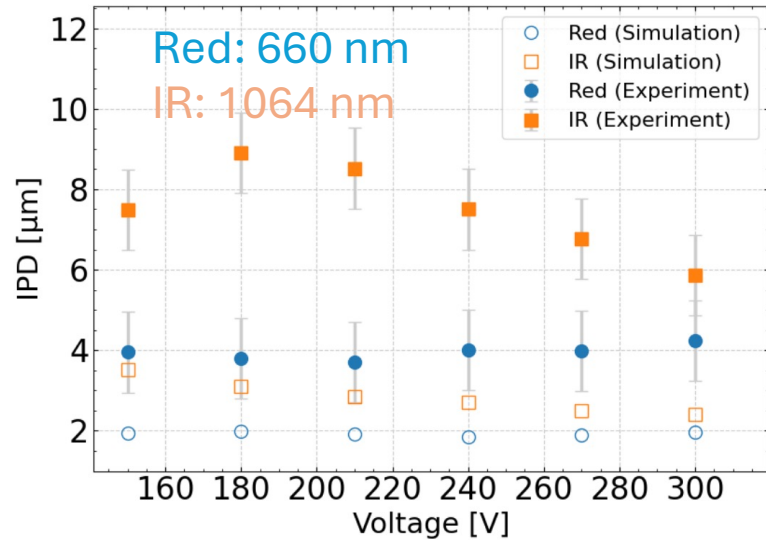
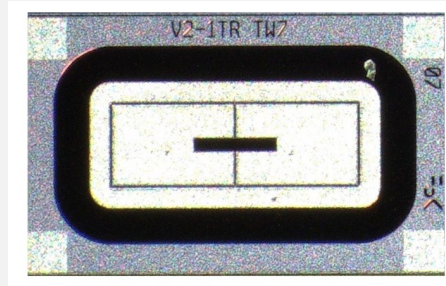
Trench-Isolated LGAD (TI-LGAD)

A. Carrera @ Trento 2026

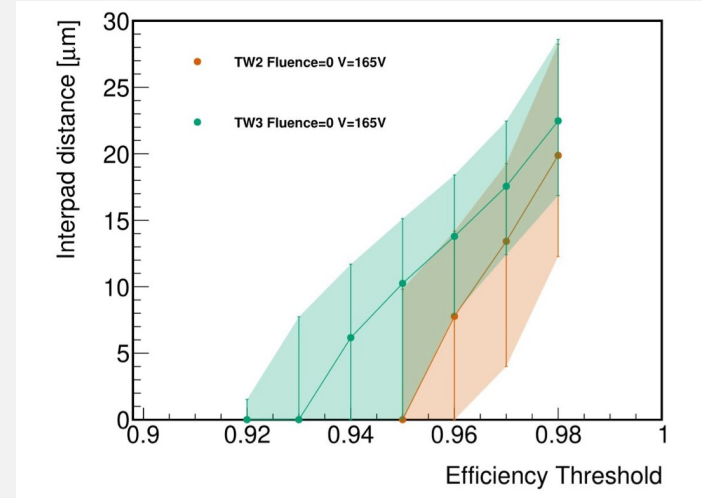
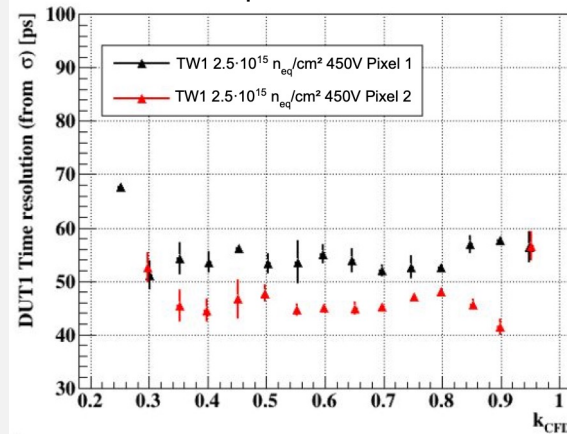
Micron Semiconductor Ltd.



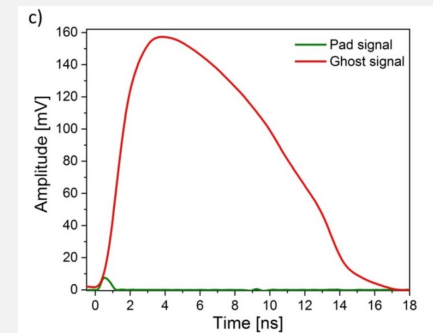
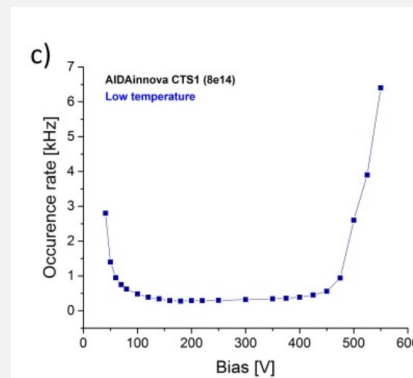
FBK AIDAInnova



$2.5 \cdot 10^{15} n_{eq}/cm^2$ ($V = 450$ V)



Self induced signal after irradiation



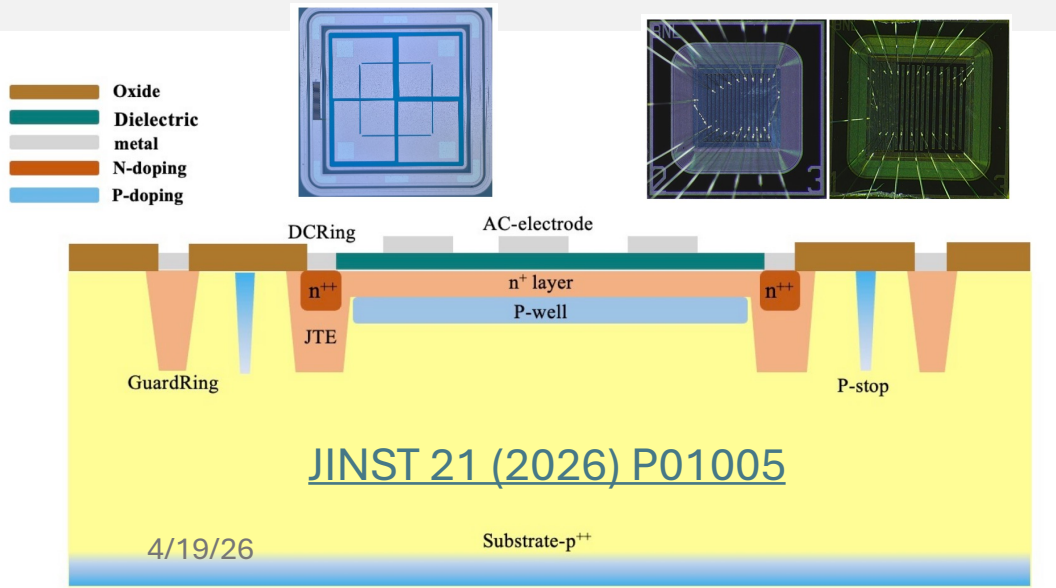
AC-LGAD

- Continuous gain layer, segmented electrodes
 - Solve the fill factor issue
 - Flexibilities in sensor design
 - Capacitively coupled readout: charge sharing

HPK: Pad size $500\ \mu\text{m} \times 500\ \mu\text{m}$ inter-pad gap: 20,30,40,50 μm Thickness 50 μm

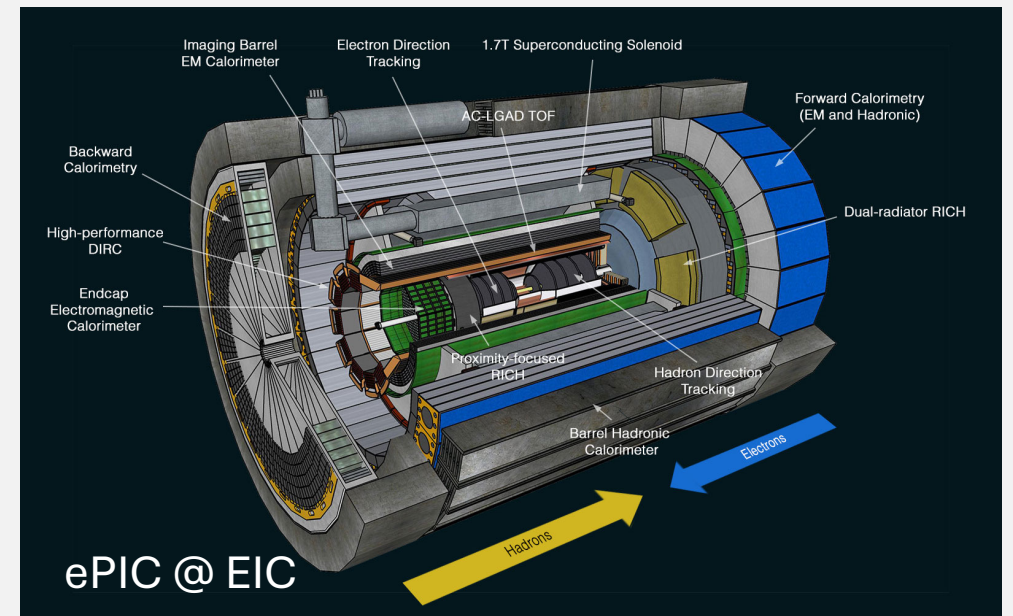
BNL: Pitch: 100/150/200 μm , strip: 80 $\mu\text{m} \times 1.7\ \text{mm}$ thickness: 50 μm

[2022 JINST 17 P05001](#)

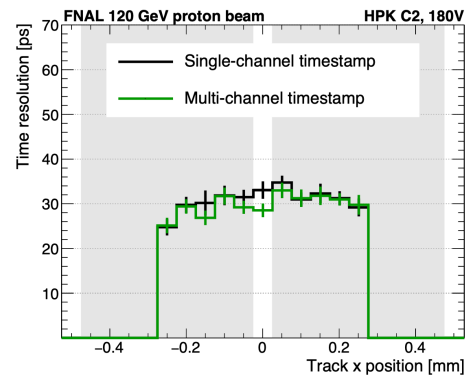
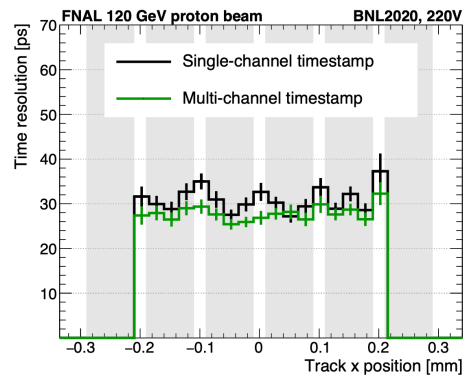
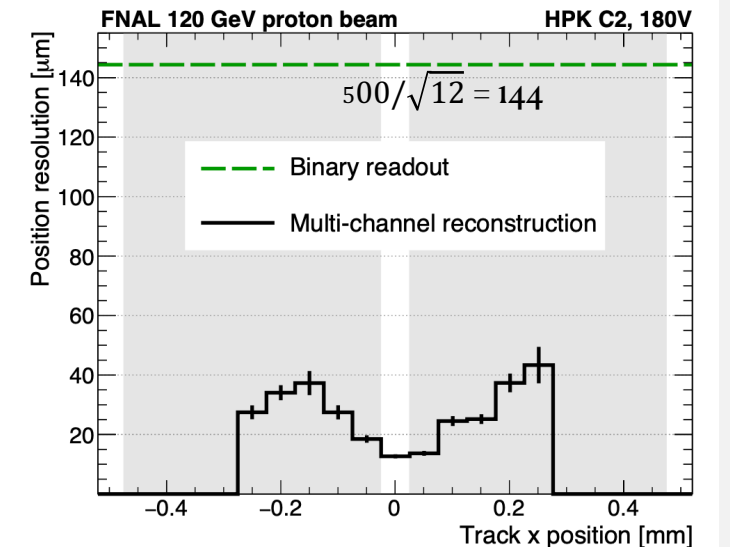
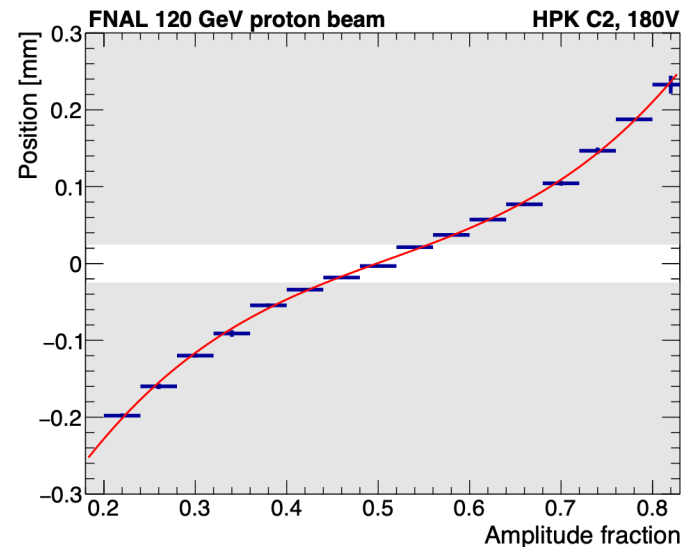
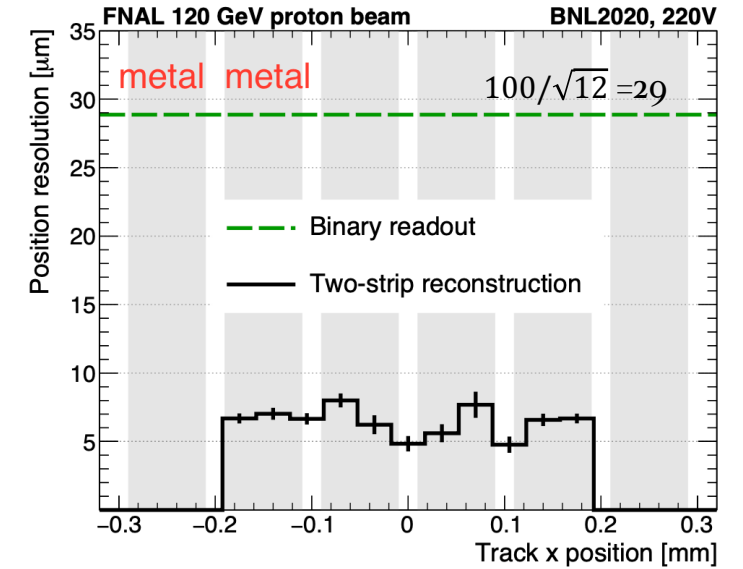
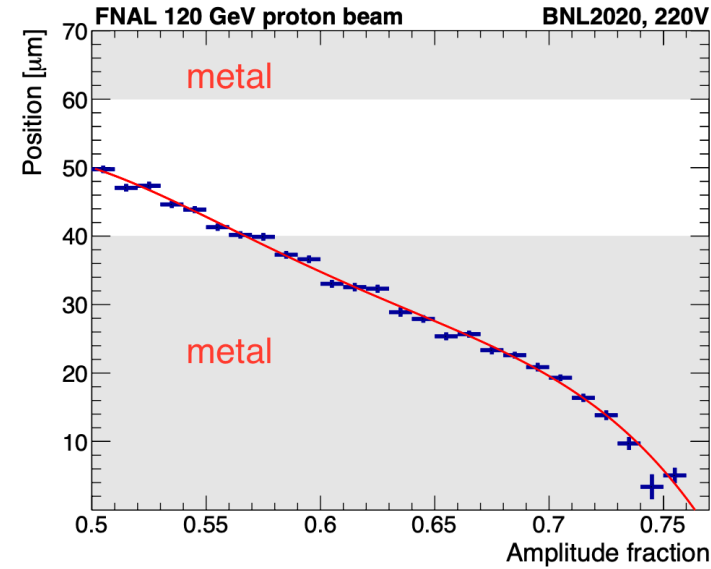
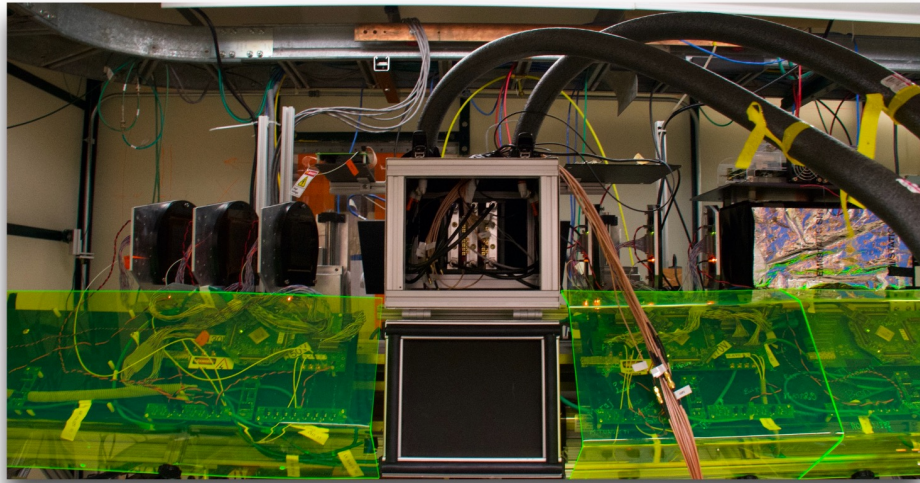
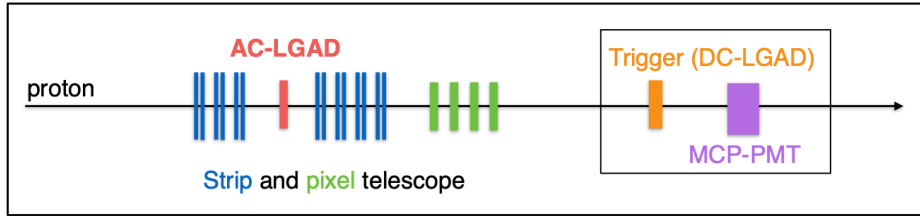


EIC requirement

Subsystem	Timing	Spatial	Geometry
Barrel TOF	~30 ps	~30 μm	1 cm strip, 500-1000 μm pitch
Forward TOF	~25 ps	~30 μm	500 x 500 μm^2 pixels

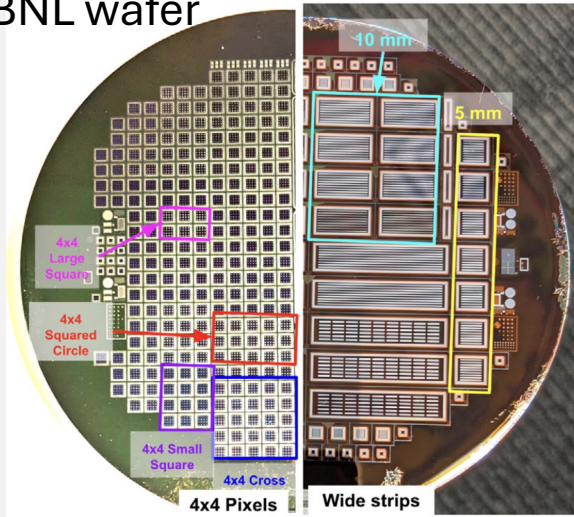


Performance from test beam(prototypes)

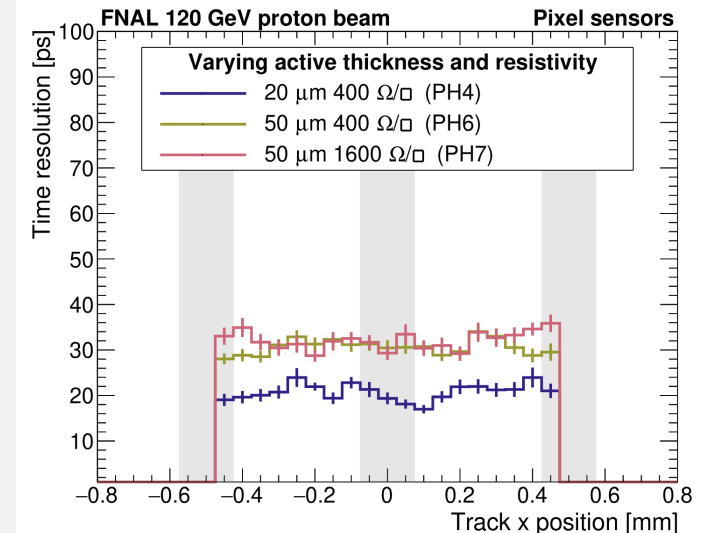
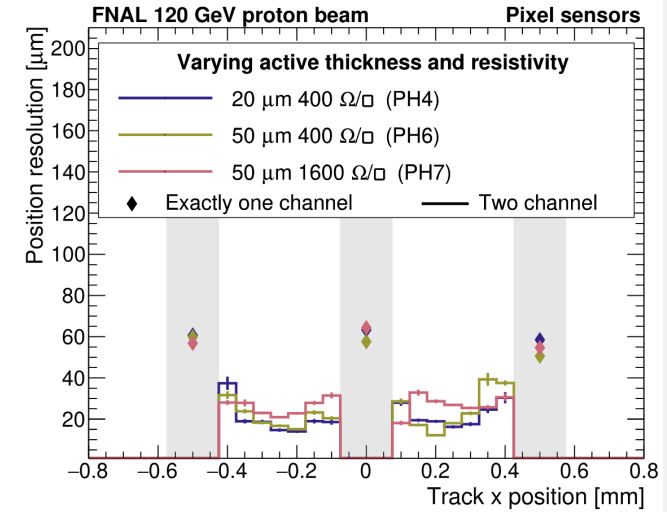
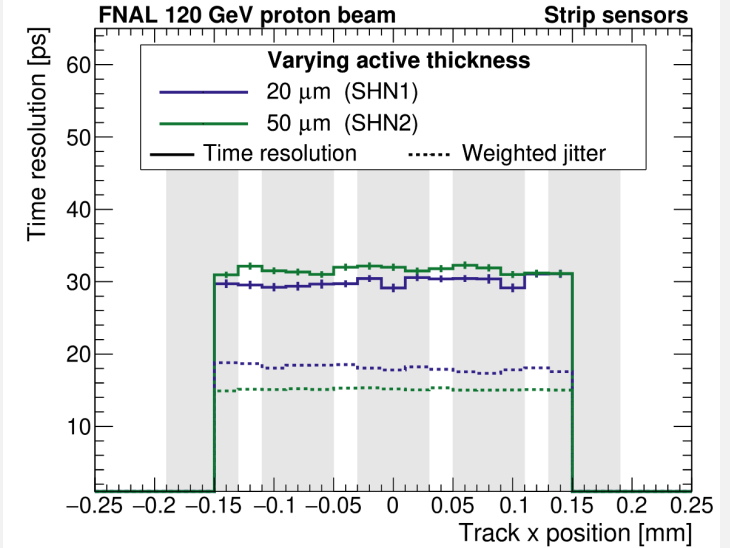
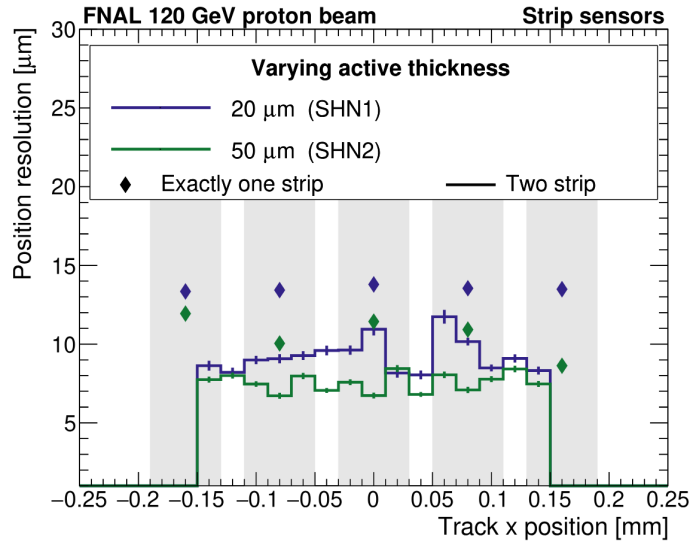
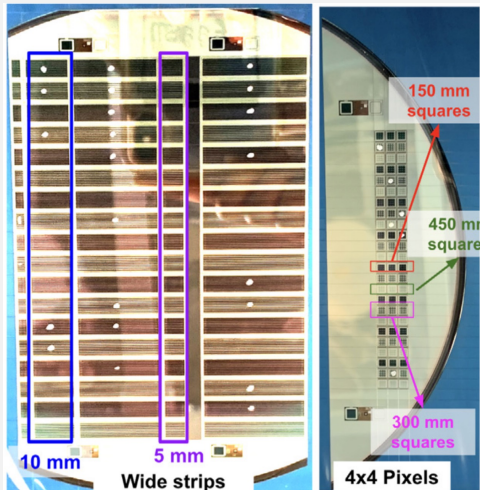


Test results of **cm-scale** AC-LGAD for ePIC

BNL wafer



HPK wafer



R&D mostly completed. Large-scale production and testing on-going

AC-LGAD R&D at USTC

- USTC made some AC-LGAD in house during the R&D for ATLAS HGTD
- Finished characterization and started developing AC-LGAD for EICC

V1: thickness = 50 μm

[JINST 21\(2026\)P01005](#)

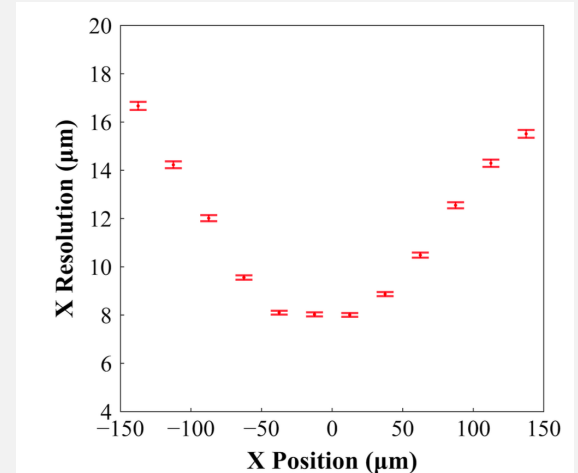
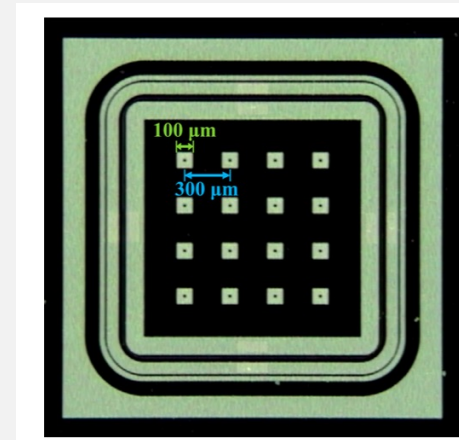
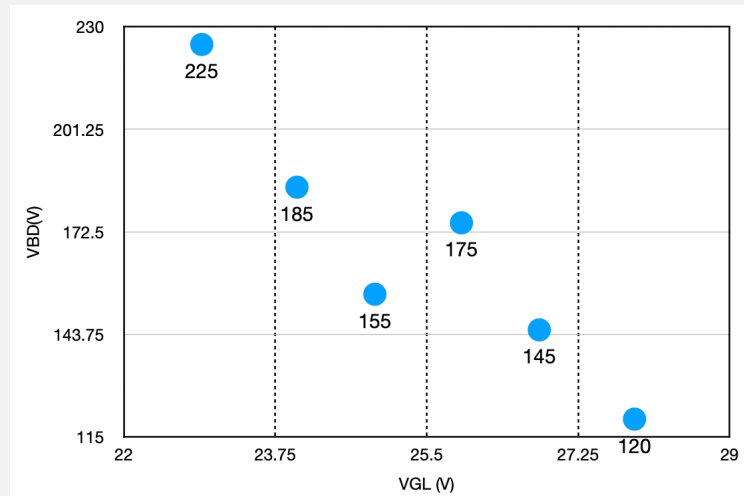
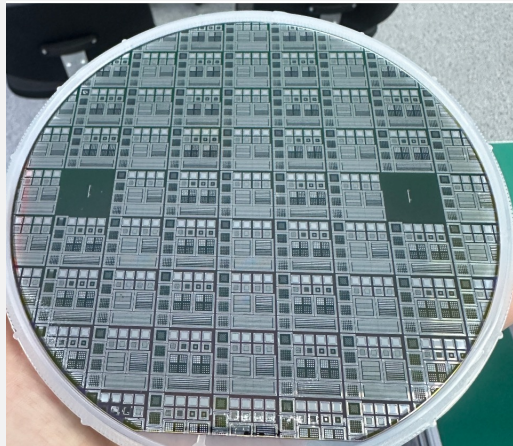
V2: thickness = 35 μm

Characterization on-going

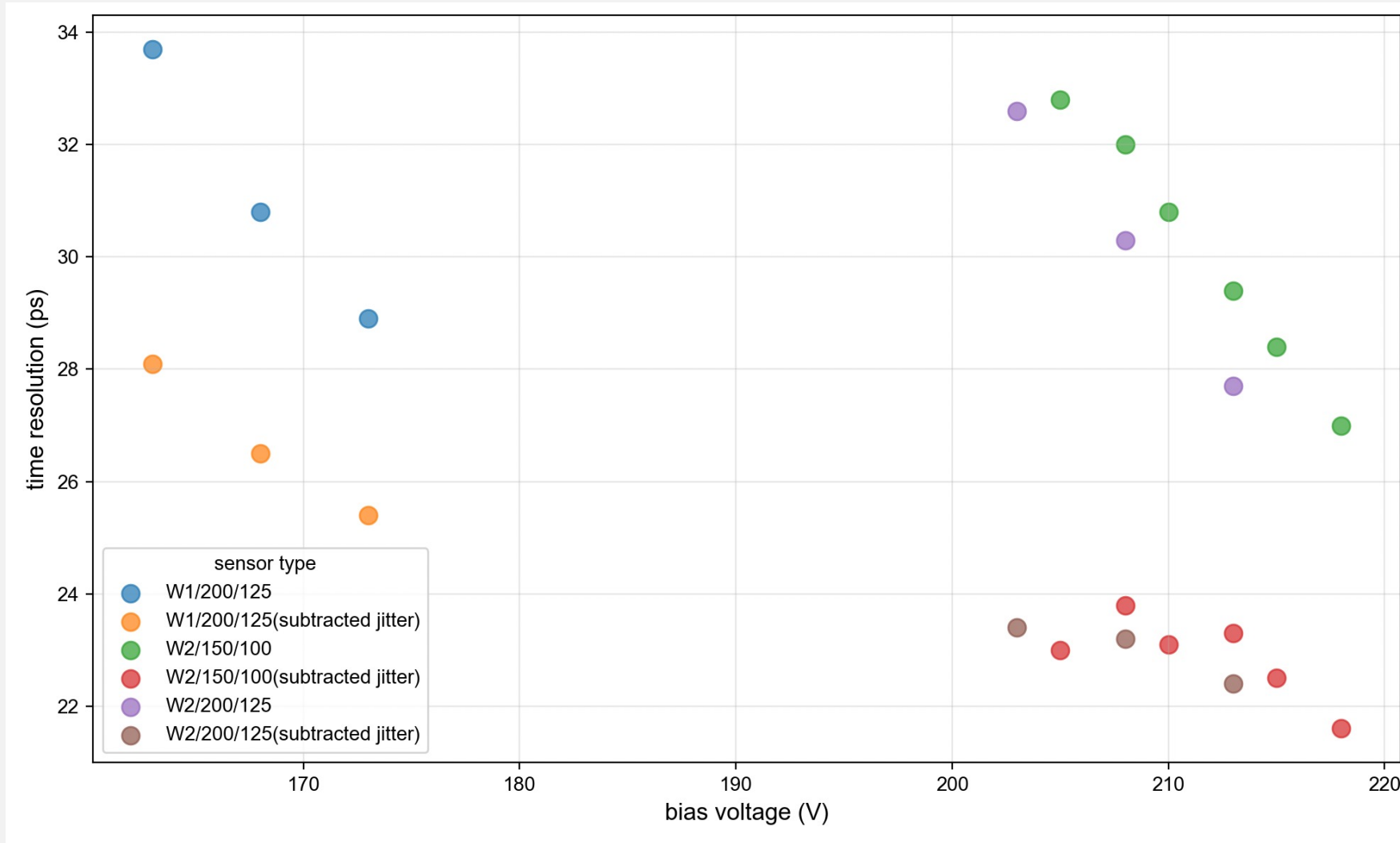
6 splits, very good correlation of VBD~VGL

[ChinaXiv:202602.00195V1](#)

ML on waveform



Very Preliminary Results on time resolution



1.2 mm strips

Readout ASIC chips for LGAD

ASIC	Process	Electronics jitter	Sensor type	Application
ETROC	65 nm	~25 ps	LGAD	CMS MTD ETL
ALTIROC	130 nm	~30 ps	LGAD	ATLAS HGTD
TOFHIR2	130 nm	30–60 ps	SiPM + Crystal	CMS MTD BTL
EICROC	130 nm	~30 ps	AC-LGAD	EIC ePIC TOF
FCFD	65 nm	~10 ps	LGAD / AC-LGAD	EIC ePIC TOF
TIMESPOT1	28 nm	~7 ps	3D Trench / LGAD	Demonstrator
PICOPIX	28 nm	~20 ps	3D Trench / LGAD	LHCb VELO II
SAMPIC/ASOC	130–65 nm	<10 ps	MCP-PMT / SiPM	TORCH, small systems

Development of ASIC in China

LATRIC (IHEP)

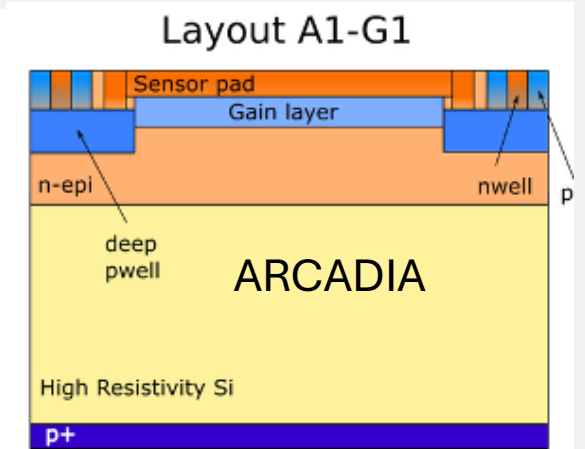
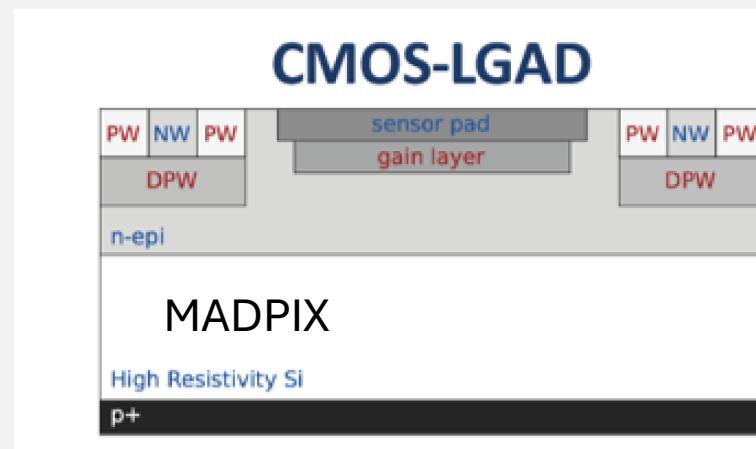
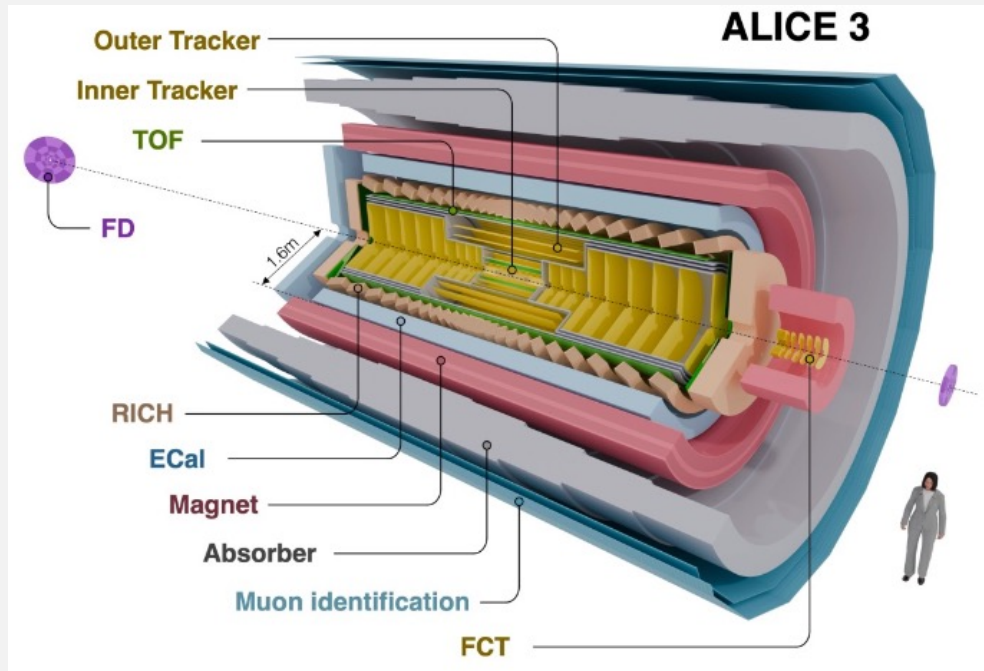
LATIC (USTC)

ALGROC (NWPU)

...

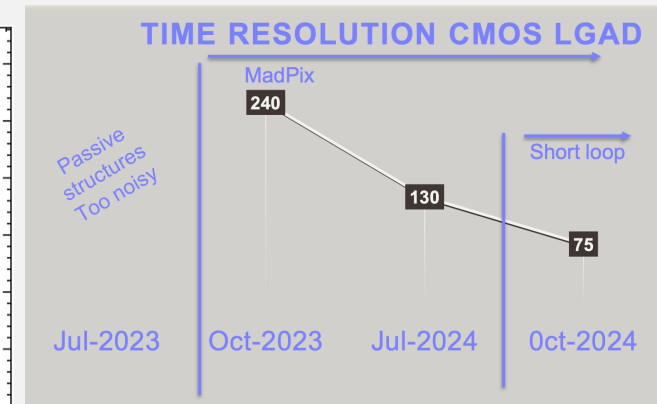
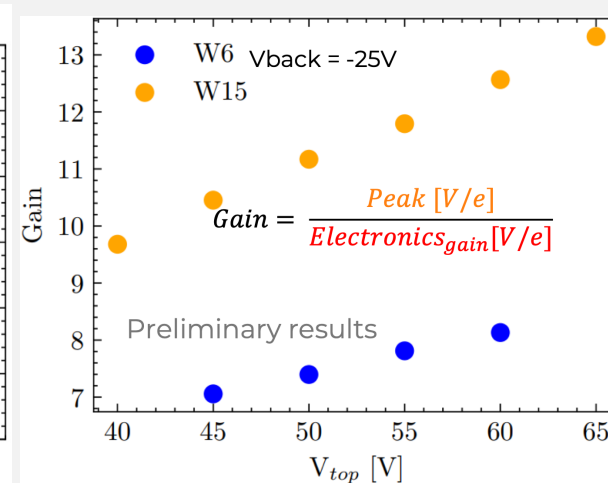
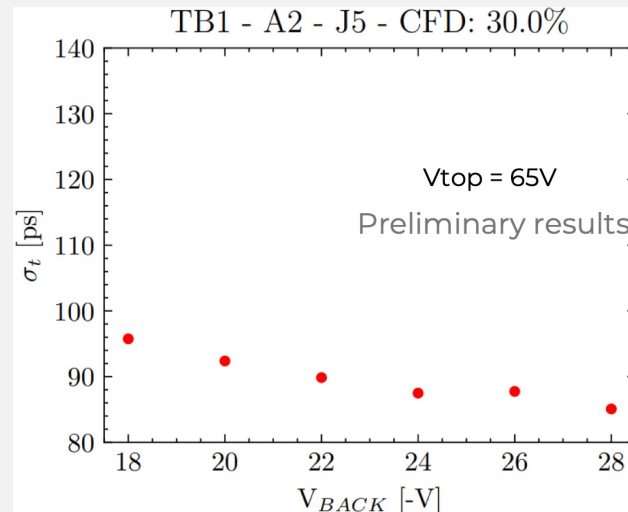
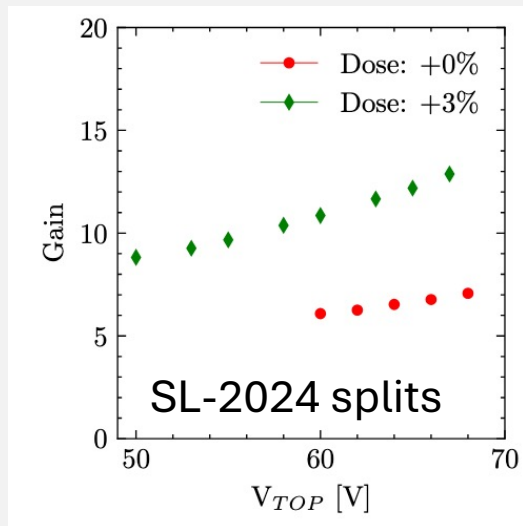
CMOS-LGAD / Monolithic LGAD

- Implement both sensor and IC on a same silicon wafer
- Application for ALICE LS4 upgrade (2034 ~ 2035)
 - Requirements: $\sigma_t \leq 20$ ps, power consumption: 50 mW/cm²



Status of MadPix for ALICE 3

- ER-2023: $\sigma_t = 120$ ps, power consumption 0.17 mW/ch gain ~ 3 , $48 \mu\text{m}$
- SL-2024: calibrated the gain to 10-20 $\sigma_t = 75$ ps (subtracted jitter)
- SL-2025: thickness = $15 \mu\text{m}$, expect ~ 30 ps time resolution
- ER-2027: full-size chip, optimal pitch to achieve 20 ps
- Backup solution: hybrid LGAD being developed at USTC



Summary

- Very intensive R&D of LGAD technology in the past 10+ years
- Extremely good progress (excellent teamwork of the community!)
- DC-LGAD → AC-LGAD → CMOS LGAD
- Current state-of-art resolutions: 20 ~ 40 ps / ~10 μm
- Applications at Collider experiments
 - LHC-LHC (pile-up mitigation)
 - EIC (TOF for PID)
 - Future (4D –tracking)